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Welcome to SmartDebug

Introduction to SmartDebug

Design debug is a critical phase of FPGA design flow. Microsemi’s SmartDebug tool complements design simulation by allowing verification and troubleshooting at the hardware level. SmartDebug provides access to non-volatile memory (eNVM), SRAM, SERDES, and probe capabilities. Microsemi SmartFusion2 System-on-chip (SoC) field programmable gate array (FPGA), IGLOO2 FPGA, and RTG4 FPGA devices have built-in probe logic that greatly enhance the ability to debug logic elements within the device. SmartDebug accesses the built-in probe points through the Active Probe and Live Probe features, which enables designers to check the state of inputs and outputs in real-time without re-layout of the design.

Use Models

SmartDebug can be run in the following modes:
- Integrated mode from the Libero Design Flow
- Standalone mode
- Demo mode

Integrated Mode
When run in integrated mode from Libero, SmartDebug can access all design and programming hardware information. No extra setup step is required. In addition, the Probe Insertion feature is available in Debug FPGA Array.

To open SmartDebug in the Libero Design Flow window, expand Debug Design and double-click SmartDebug Design.

Standalone Mode
SmartDebug can be installed separately in the setup containing FlashPro, FlashPro Express, and Job Manager. This provides a lean installation that includes all the programming and debug tools to be installed in a lab environment for debug. In this mode, SmartDebug is launched outside of the Libero Design Flow. When launched in standalone mode, you must go through SmartDebug project creation and import a Design Debug Data Container (DDC) file, exported from Libero, to access all debug features in the supported devices.

Note: In standalone mode, the Probe Insertion feature is not available in FPGA Array Debug, as it requires incremental routing to connect the user net to the specified I/O.

Demo Mode
Demo mode allows you to experience SmartDebug features (Active Probe, Live Probe, Memory Blocks, SERDES) without connecting a board to the system running SmartDebug.

Note: SmartDebug demo mode is for demonstration purposes only, and does not provide the functionality of integrated mode or standalone mode.

Note: You cannot switch between demo mode and normal mode while SmartDebug is running.

Standalone Mode Use Model Overview

In the main use model for standalone SmartDebug, the DDC file must be generated from Libero and imported into a SmartDebug project to obtain full access to the device debug features. Alternatively, SmartDebug can be used without a DDC file with a limited feature set.
Supported Families, Programmers, and Operating Systems

Programming and Debug: SmartFusion2, IGLOO2, and RTG4
Programming only: ProAsic3/E, IGLOO, Fusion, and SmartFusion
Programmers: FlashPRO3, FlashPRO4, and FlashPRO5
Operating Systems: Windows XP, Windows 7, Windows 10, and RHEL 6.x

Note: Debug for ProAsic3/E, IGLOO, Fusion, and SmartFusion devices are available via FlashPro. Also refer to "Inspect Device" in the "Device Debug User Interface" section of the FlashPro User Guide.

Supported Tools

The following table lists device family support for SmartDebug tools.

<table>
<thead>
<tr>
<th>SmartDebug Support per Device Family</th>
<th>SmartFusion2</th>
<th>IGLOO2</th>
<th>RTG4</th>
<th>SmartFusion</th>
<th>Fusion</th>
</tr>
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<tbody>
<tr>
<td>Live Probes</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>Active Probes</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>Memory Debug</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>Probe Insertion (available only through Libero flow)</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>View Flash Memory Content</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>Debug SERDES</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td></td>
</tr>
<tr>
<td>FPGA Hardware Breakpoint (Needs FHB Auto Instantiation)</td>
<td>X</td>
<td>X</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Event Counter (Needs FHB Auto Instantiation)</td>
<td>X</td>
<td>X</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Frequency Monitor (Needs FHB Auto Instantiation)</td>
<td>X</td>
<td>X</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>FlashROM</td>
<td>X</td>
<td>X</td>
<td></td>
<td>X</td>
<td>X</td>
</tr>
<tr>
<td>Analog Block Configuration</td>
<td>X</td>
<td>X</td>
<td></td>
<td>X</td>
<td></td>
</tr>
</tbody>
</table>

Note: “X” indicates the tool is supported.

Getting Started with SmartDebug

This topic introduces the basic elements and features of SmartDebug. If you are already familiar with the user interface, proceed to the Solutions to Common Issues Using SmartDebug or Frequently Asked Questions sections.

SmartDebug enables you to use JTAG to interrogate and view embedded silicon features and device status (FlashROM, Security Settings, Embedded Flash Memory (NVM) and Analog System). SmartDebug is available as a part of the FlashPro programming tool.

See Using SmartDebug and Using SmartDebug with SmartFusion2, IGLOO2, and RTG4 for an overview of the use flow.

See Using SmartDebug for an overview of the use flow.
You can use the debugger to:

- Get device status and view diagnostics
- Use the FlashROM debug GUI to read out and compare content
- Use the Embedded Flash Memory Debug GUI to read out and compare your content with your original files
- Use the Analog System Debug to read out and compare your analog block configuration with your original file

Using SmartDebug with SmartFusion and Fusion

**Note**: SmartDebug is referred to as Device Debug in some older families.

The most common flow for SmartDebug is:

1. **Start FlashPro**. If necessary, **create a new project**. You must have a FlashPro programmer connected to use SmartDebug.
2. Set up your FlashPro Project with or without a PDB file. If you are in single-device mode you will need a PDB file. You can create a PDB file in both Single Device and Chain mode.

   With a PDB, you will get additional information such as FlashROM and Embedded Flash Memory partitions when debugging the silicon features. Best practice is to use a PDB with a valid-use design to start a debug session.
3. Select the target device from your chain and click **Inspect Device**.
4. Click **Device Status** to get device status and check for issues
5. Examine individual silicon features (FlashROM, Embedded Flash Memory Block and Analog System) on the device.

Using SmartDebug with SmartFusion2, IGLOO2, and RTG4

The most common flow for SmartDebug is:

1. **Create your design**. You must have a FlashPro programmer connected to use SmartDebug.
2. Expand **Debug Design** and double-click **Smart Debug Design** in the Design Flow window. SmartDebug opens for your target device.
3. Click **View Device Status** to view the device status report and check for issues.
4. Examine individual silicon features, such as FPGA debug.

Running SmartDebug in Demo Mode

Demo mode allows you to experience SmartDebug features (Active Probe, Live Probe, Memory Blocks, SERDES) without connecting a board to the system running SmartDebug.

**Note**: SmartDebug demo mode is for demonstration purposes only, and does not provide the functionality of integrated mode or standalone mode.

**Note**: You cannot switch between demo mode and normal mode while SmartDebug is running.

If programming hardware is not detected when you invoke SmartDebug, you will see the following.
Create Standalone SmartDebug Project

A standalone SmartDebug project can be configured in two ways:

- Import DDC files exported from Libero
- Construct Automatically

From the SmartDebug main window, click Project and choose New Project. The Create SmartDebug Project dialog box opens.
Import from DDC File (created from Libero)

When you select the **Import from DDC File** option in the Create SmartDebug Project dialog box, the Design Debug Data of the target device and all hardware and JTAG chain information present in the DDC file exported in Libero are automatically inherited by the SmartDebug project. The programming file information loaded onto other Microsemi devices in the chain, including ProASIC3/E, SmartFusion, and Fusion devices, is also transferred to the SmartDebug project.

Debug data is imported from the DDC file (created through Export SmartDebug Data in Libero) into the debug project, and the devices are configured using data from the DDC file.

Construct Automatically

When you select the **Construct Automatically** option, a debug project is created with all the devices connected in the chain for the selected programmer. This is equivalent to Construct Chain Automatically in FlashPRO.

Configuring a Generic Device

For Microsemi devices having the same JTAG IDCODE (i.e., multiple derivatives of the same Die—for example, M2S090T, M2S090TS, and so on), the device type must be configured for SmartDebug to enable relevant features for debug. The device can be configured by loading the programming file, by manually selecting the device using Configure Device, or by importing DDC files through Programming Connectivity and Interface. When the device is configured, all debug options are shown.

For debug projects created using Construct Automatically, you can use the following options to debug the devices:

- Load the programming file — Right-click the device in Programming Connectivity and Interface.
- Import Debug Data from DDC file — Right-click the device in Programming Connectivity and Interface.

The appropriate debug features of the targeted devices are enabled after the programming file or DDC file is imported.
Connected FlashPRO Programmers
The drop-down lists all FlashPro programmers connected to the device. Select the programmer connected to the chain with the debug device. At least one programmer must be connected to create a standalone SmartDebug project.

Before a debugging session or after a design change, program the device through Programming Connectivity and Interface.

See Also
- Programming Connectivity and Interface
- View Device Status
- Export SmartDebug Data (from Libero)
SmartDebug User Interface

Standalone SmartDebug User Interface

You can start standalone SmartDebug from the Libero installation folder or from the FlashPRO installation folder.

Windows:
<Libero Installation folder>/Designer/bin/sdebug.exe
<FlashPRO Installation folder>/bin/sdebug.exe

Linux:
<Libero Installation folder>/bin/sdebug
<FlashPRO Installation folder>/bin/sdebug

Figure 2 · Standalone SmartDebug Main Window

Project Menu
The Project menu allows you do the following:

- Create new SmartDebug projects (Project > New Project)
- Open existing debug projects (Project > Open Project)
• Execute SmartDebug-specific Tcl scripts (Project > Execute Script)
• Export SmartDebug-specific commands to a script file (Project > Export Script File)
• See a list of recent SmartDebug projects (Project > Recent Projects).

Log Window
SmartDebug displays the Log window by default when it is invoked. To suppress the Log window display, click the View menu and toggle View Log.

The Log window has four tabs:
- **Messages** – displays standard output messages
- **Errors** – displays error messages
- **Warnings** – displays warning messages
- **Info** – displays general information

Tools Menu
The Tools menu includes Programming Connectivity and Interface and Programmer Settings options, which are enabled after creating or opening a SmartDebug project.

Programming Connectivity and Interface
To open the Programming Connectivity and Interface dialog box, from the standalone SmartDebug Tools menu, choose Programming Connectivity and Interface. The Programming Connectivity and Interface dialog box displays the physical chain from TDI to TDO.

![Programming Connectivity and Interface](image)

Figure 3 · Programming Connectivity and Interface Dialog Box – Project created using Import from DDC File

All devices in the chain are disabled by default when a standalone SmartDebug project is created using the Construct Automatically option in the Create SmartDebug Project dialog box.

![Programming Connectivity and Interface](image)

Figure 4 · Programming Connectivity and Interface window – Project created using Construct Automatically
The Programming Connectivity and Interface dialog box includes the following actions:

- **Construct Chain Automatically** - Automatically construct the physical chain.
  
  Running Construct Chain Automatically in the Programming Connectivity and Interface removes all existing debug/programming data included using DDC/programming files. The project is the same as a new project created using the Construct Chain Automatically option.

- **Scan and Check Chain** – Scan the physical chain connected to the programmer and check if it matches the chain constructed in the scan chain block diagram.

- **Run Programming Action** – Option to program the device with the selected programming procedure.

  When two devices are connected in the chain, the programming actions are independent of the device. For example, if M2S090 and M2GL010 devices are connected in the chain, and the M2S090 device is to be programmed and the M2GL010 device is to be erased, both actions can be done at the same time using the Run Programming Action option.

- **Zoom In** – Zoom into the scan chain block diagram.

- **Zoom Out** – Zoom out of the scan chain block diagram.

**Hover Information**

The device tooltip displays the following information if you hover your cursor over a device in the scan chain block diagram:

- **Name**: User-specified device name. This field indicates the unique name specified by the user in the Device Name field in Configure Device (right-click Properties).

- **Device**: Microsemi device name.

- **Programming File**: Programming file name.

- **Programming action**: The programming action selected for the device in the chain when a programming file is loaded.

- **IR**: Device instruction length.

- **TCK**: Maximum clock frequency in MHz to program a specific device; standalone SmartDebug uses this information to ensure that the programmer operates at a frequency lower than the slowest device in the chain.
Device Chain Details

The device within the chain has the following details:

- User-specified device name
- Device name
- Programming file name
- Programming action – Select Enable Device for Programming to enable the device for programming. Enabled devices are green, and disabled devices are grayed out.

Right-click Properties

The following options are available when you right-click a device in the Programming Connectivity and Interface dialog box.

Configure Device - Ability to reconfigure the device.
- Family and Die: The device can be explicitly configured from the Family, Die drop-down.
- Device Name: Editable field for providing user-specified name for the device.

Enable Device for Programming - Select to enable the device for programming. Enabled devices are shown in green, and disabled devices are grayed out.

Load Programming File - Load the programming file for the selected device.

Select Programming Procedure/Actions - Option to select programming action/procedures for the devices connected in the chain.
- Actions: List of programming actions for your device.
- Procedures: Advanced option; enables you to customize the list of recommended and optional procedures for the selected action.

Import Debug Data from DDC File - Option to import debug data information from the DDC file.

The DDC file selected for import into device must be created for a compatible device. When the DDC file is imported successfully, all current device debug data is removed and replaced with debug data from the imported DDC file. The JTAG Chain configuration from the imported DDC file is ignored in this option.

If a programming file is already loaded into the device prior to importing debug data from the DDC file, the programming file content is replaced with the content of the DDC file (if programming file information is included in the DDC file).

Debug Context Save

Debug context refers to the user selections in debug options such as Debug FPGA Array, Debug SERDES, and View Flash Memory Content. In standalone SmartDebug, the debug context of the current session is saved or reset depending on the user actions in Programming Connectivity and Interface.
The debug context of the current session is retained for the following actions in Programming Connectivity and Interface:

- Enable Device for Programming
- Select Programming Procedure/Actions
- Scan and Check Chain
- Run Programming Action

The debug context of the current session is reset for the following actions in Programming Connectivity and Interface:

- Auto Construct – Clears all the existing debug data. You need to reimport the debug data from DDC file.
- Import Debug Data from DDC file
- Configure Device – Renaming the device in the chain
- Configure Device – Family/Die change
- Load Programming File

Selecting Devices for Debug

Standalone SmartDebug provides an option to select the devices connected in the JTAG chain for debug. The device debug context is not saved when another debug device is selected.

View Device Status (SmartFusion2, IGLOO2, and RTG4)

Click **View Device Status** in the standalone SmartDebug main window to display the Device Status Report. The Device Status Report is a complete summary of IDCode, device certificate, design information, programming information, digest, and device security information. Use this dialog box to save or print your information for future reference.
**IdCode**

IdCode read from the device under debug.

**Device Certificate**

Device certificate displays Family and Die information if device certificate is installed on the device. If the device certificate is not installed on the device, a message indicating that the device certificate may not have been installed is shown.
Design Information
Design Information displays the following:
- Design Name
- Design Checksum
- Design Version
- Back Level (SmartFusion2 and IGLOO2 only)
- Operating Voltage (SmartFusion2 and IGLOO2 only)
- Internal Oscillator (SmartFusion2 and IGLOO2 only)

Digest Information
Digest Information displays Fabric Digest, eNVM_0 Digest and eNVM_1 Digest (for M2S090 and M2S150 devices only) computed from the device during programming. eNVM Digest is shown when eNVM is used in the design.

Device Security Settings
Note: For RTG4 devices, only Lock Bit information is displayed.
Device Security Settings indicate the following:
- Factory test mode access
- Power on reset delay
- System Controller Suspend Mode
In addition, if custom security options are used, Device Security Settings indicate:
- User Lock segment is protected
- User Pass Key 1/2 encrypted programming is enforced for the FPGA Array
- User Pass Key 1/2 encrypted programming is enforced for the eNVM_0 and eNVM_1
- SmartDebug write access to Active Probe and AHB mem space
- SmartDebug read access to Active Probe, Live Probe & AHB mem space
- UJTAG access to fabric

Programming Information
Programming Information displays the following:
- Cycle Count
- VPP Range
- Temp Range
- Algorithm Version
- Programmer
- Software Version
- Programming Software
- Programming Interface Protocol
- Programming File Type

Demo Mode
The following figure shows an example of the Device Status Report in Demo Mode.
Embedded Flash Memory (NVM) Content Dialog Box (SmartFusion2 and IGLOO2 Only)

The NVM content dialog box is divided into two sections:
- View content of Flash Memory pages (as shown in the figure below)
- Check page status and identify if a page is corrupted or if the write count limit has exceeded the 10-year retention threshold

Choose the eNVM page contents to be viewed by specifying the page range (i.e., start page and the end page) and click Read from Device to view the values.

You must click Read from Device each time you specify a new page range to update the view.

Specify a page range if you wish to examine a specific set of pages. In the Retrieved Data View, you can enter an Address value (such as 0010) in the Go to Address field and click the corresponding button to go directly to that address. Page Status information appears to the right.
Contents of Page Status

- ECC1 detected and corrected
- ECC2 detected
- Write count of the page
  - If write count has exceeded the threshold
  - If the page is used as ROM (first page lock)
- Overwrite protect (second page lock)
- Flash Freeze state (deep power down)

Figure 7 · Flash Memory Dialog Box for a SmartFusion2 Device (SmartDebug)

The page status gets updated when you:

- Click Page Range
- Click a particular cell in the retrieved eNVM content table
- Scroll pages from the keyboard using the Up and Down arrow keys
- Click Go to Address (hex)

The retrieved data table displays the content of the page range selection. If content cannot be read (for example, pages are read-protected, but security has been erased or access to eNVM private sectors), Read from Device reports an error.

Click View Detailed Status for a detailed report on the page range you have selected.

For example, if you want to view a report on pages 1-3, set the Start Page to 1, set the End Page to 3, and click Read from Device. Then click View Detailed Status. The figure below is an example of the data for a specific page range.
Figure 8 · Flash Memory Details Dialog Box (SmartDebug)
Debugging

Debug FPGA Array (SmartFusion2, IGLOO2, and RTG4)

In the Debug FPGA Array dialog box, you can view your Live Probes, Active Probes, Memory Blocks, and Insert Probes (Probe Insertion).

The Debug FPGA Array dialog box includes the following four tabs:

- Live Probes
- Active Probes
- Memory Blocks
- Probe Insertion

It also includes the FPGA Hardware Breakpoint (FHB) controls, consisting of the following tabs:

- "Event Counter" on page 42
- "Frequency Monitor" on page 45
- "User Clock Frequencies" on page 54

Hierarchical View

The Hierarchical View lets you view the instance level hierarchy of the design programmed on the device and select the signals to add to the Live Probes, Active Probes, and Probe Insertion tabs in the Debug FPGA Array dialog box. Logical and physical Memory Blocks can also be selected.

- **Instance** – Displays the probe points available at the instance level.
- **Primitives** – Displays the lowest level of probeable points in the hierarchy for the corresponding component —i.e., leaf cells (hard macros on the device).

You can expand the hierarchy tree to see lower level logic.

Signals with the same name are grouped automatically into a bus that is presented at instance level in the instance tree.

The probe points can be added by selecting any instance or the leaf level instance in the Hierarchical View. Adding an instance adds all the probe able points available in the instance to Live Probes, Active Probes, and Probe Insertion.
Figure 9 · Hierarchical View
Search
In Live Probes, Active Probes, Memory Blocks, and the Probe Insertion UI, a search option is available in the Hierarchical View. You can use wildcard characters such as * or ? in the search column for wildcard matching.

Probe points of leaf level instances resulting from a search pattern can only be added to Live Probes, Active Probes, and the Probe Insertion UI. You cannot add instances of search results in the Hierarchical View.

Netlist View
The Netlist View displays a flattened net view of all the probe-able points present in the design, along with the associated cell type.
A search option is available in the Netlist View for Live Probes, Active Probes, and Probe Insertion. You can use wildcard characters such as * or ? in the search column for wildcard matching.
Live Probes (SmartFusion2, IGLOO2, and RTG4)

Live Probes is a design debug option that uses non-intrusive real time scoping of up to two probe points with no design changes.

The Live Probes tab in the Debug FPGA Array dialog box displays a table with the probe names and pin types.

**Note:** SmartFusion2 and IGLOO2 support two probe channels, and RTG4 supports one probe channel.

**SmartFusion2 and IGLOO2**

Two probe channels (ChannelA and ChannelB) are available. When a probe name is selected, it can be assigned to either ChannelA or ChannelB.

You can assign a probe to a channel by doing either of the following:

- Right-click a probe in the table and choose **Assign to Channel A** or **Assign to Channel B**.
- Click the **Assign to Channel A** or **Assign to Channel B** button to assign the probe selected in the table to the channel. The buttons are located below the table.

When the assignment is complete, the probe name appears to the right of the button for that channel, and SmartDebug configures the ChannelA and ChannelB I/Os to monitor the desired probe points. Because there are only two channels, a maximum of two internal signals can be probed simultaneously.

Click the **Unassign Channels** button to clear the live probe names to the right of the channel buttons and discontinue the live probe function during debug.

**Note:** At least one channel must be set; if you want to use both probes, they must be set at the same time.

![Live Probes Tab (SmartFusion2 and IGLOO2) in SmartDebug FPGA Array Dialog Box](image)

**RTG4**

One probe channel (Probe Read Data Pin) is available for RTG4 for debug. When a probe name is selected, it can be assigned to the Probe Channel (Probe Read Data Pin).

You can assign a probe to a channel by doing either of the following:

- Right-click a probe in the table and choose **Assign to Probe Read Data Pin**.
- Click the **Assign to Probe Read Data Pin** button to assign the probe selected in the table to the channel. The button is located below the table.

Click the **Unassign probe read data pin** button to clear the live probe name to the right of the channel button and discontinue the live probe function during debug.
The Active Probes READ/WRITE overwrites the settings of Live Probe channels (if any).

Live Probes in Demo Mode
You can assign and unassign Live Probes ChannelA and ChannelB. See the following example figure.

Active Probes (SmartFusion2, IGLOO2, and RTG4)
Active Probes is a design debug option to read and write to one or many probe points in the design through JTAG.
In the left pane of the Active Probes tab, all available Probe Points are listed in instance level hierarchy in the Hierarchical View. All Probe Names are listed with the Name and Type (which is the physical location of the flip-flop) in the Netlist View.
Select probe points from the Hierarchical View or Netlist View, right-click and choose Add to add them to the Active Probes UI. You can also add the selected probe points by clicking the Add button. The probes list can be filtered with the Filter box.
When you have selected the desired probe, points appear in the Active Probe Data chart and you can read and write multiple probes (as shown in the figure below).

You can use the following options in the Write Value column to modify the probe signal added to the UI:

- Drop-down menu with values ‘0’ and ‘1’ for individual probe signals
- Editable field to enter data in hex or binary for a probe group or a bus
Active Probes in Demo Mode

In demo mode, a temporary probe data file with details of current and previous values of probes added in the active probes tab is created in the designer folder. The write values of probes are updated to this file, and the GUI is updated with values from this file when you click Write Active Probes. Data is read from this file when you click Read Active Probes. If there is no existing data for a probe in the file, the read value displays all 0s. The value is updated based on your changes.

See the following example figure.

![Active Probes in Demo Mode](image)

Probe Grouping (Active Probes Only)

During the debug cycle of the design, designers often want to examine the different signals. In large designs, there can be many signals to manage. The Probe Grouping feature assists in comprehending multiple signals as a single entity. This feature is applicable to Active Probes only. Probe nets with the same name are automatically grouped in a bus when they are added to the Active Probes tab. Custom probe groups can also be created by manually selecting probe nets of a different name and adding them into the group.

The Active Probes tab provides the following options for probe points that are added from the Hierarchical View/Netlist View:

- Display bus name. An automatically generated bus name cannot be modified. Only custom bus names can be modified.
- Expand/collapse bus or probe group
- Move Up/Down the signal, bus, or probe group
- Save (Active Probes list)
- Load (already saved Active Probes list)
- Delete (applicable to a single probe point added to the Active Probes tab)
- Delete All (deletes all probe points added to the Active Probes tab)
- In addition, the context (right-click) menu provides the following operations:
  - Create Group, Add/Move signals to Group, Remove signals from Group,
  - Ungroup
  - Reverse bit order, Change Radix for a bus or probe group
  - Read, Write, or Delete the signal or bus or probe group
Green entries in the “Write Value” column indicate that the operation was successful.  
Blue entries in the “Read Value” column indicate values that have changed since the last read.

**Context Menu of Probe Points Added to the Active Probes UI**

When you right-click a signal or bus, you will see the following menu options:

*For individual signals that are not part of a probe group or bus:*

- Read
- Write
- Delete
- Poll
- Create Group
- Add to Group
- Move to Group
For individual signals in a probe group:

- Read
- Delete
- Poll
- Create Group
- Add to Group
- Move to Group
- Remove from Group

For individual signals in a bus:

- Read
- Delete
- Poll
- Create Group
- Add to Group
For a bus:
- Delete
- Reverse Bit Order
- Change Radix to Binary
- Poll
- Create Group

For a probe group:
- Delete
- Reverse Bit Order
- Change Radix to Binary
- Poll
- Create Group
- Ungroup
Differences Between a Bus and a Probe Group

A bus is created automatically by grouping selected probe nets with the same name into a bus. A bus cannot be ungrouped.

A Probe Group is a custom group created by adding a group of signals in the Active Probes tab into the group. The members of a Probe Group are not associated by their names. A Probe Group can be ungrouped.

In addition, certain operations are also restricted to the member of a bus, whereas they are allowed in a probe group.

The following operations are not allowed in a bus:

- **Move to Group**: Moving a signal to a probe group
- **Remove from Group**: Removing a signal from a probe group

Memory Blocks (SmartFusion2, IGLOO2, and RTG4)

The Memory Blocks tab in the Debug FPGA Array dialog box shows the hierarchical view of all memory blocks in the design. The depth and width of blocks shown in the logical view are determined by the user in SmartDesign, RTL, or IP cores using memory blocks.

**Notes:**

- RAM is not accessible to the user when SmartDebug is accessing RAM blocks.
- RAM is not accessible to the user during a read or write operation.
  - During a single location write, the RAM block is not accessible. If multiple locations are written, the RAM block is accessed and released for each write.
  - When each write is completed, access returns to the user, so the access time is a single write operation time.

The example figure that follows shows the hierarchical view of the Memory Blocks tab. You can view logical blocks and physical blocks. Logical blocks are shown with an L (\(L\)), and physical blocks are shown with a P (\(P\)).
You can only select one block at a time. You can select and add blocks in the following ways:

- Right-click the name of a memory block and click Add as shown in the following figure.
- Click on a name in the list and then click Select.
- Select a name, drag it to the right, and drop it into the Memory Blocks tab.
- Enter a memory block name in the Filter box and click Search or press Enter. Wildcard search is supported.

**Note:** Only memory blocks with an L or P icon can be selected in the hierarchical view.

### Memory Block Fields

The following memory block fields appear in the Memory Blocks tab.

#### User Design Memory Block

The selected block name appears on the right side. If the block selected is logical, the name from top of the block is shown.
Data Width
If a block is logical, the width from each physical block is retrieved from each physical block, consolidated, and displayed. If the block is physical, the width is 9-bits, and the depth is 128 for uSRAM blocks and 2048 for LSRAM blocks.

Port Used
This field is displayed only in the logical block view. Because configurators can have asymmetric ports, memory location can have different widths. The port shown can either be Port A or Port B. For TPSRAM, where both ports are used for reading, Port A is used. This field is hidden for physical blocks, as the values shown will be irrespective of read ports.

The following figure shows the Memory Blocks tab fields for a logical block view.

![Figure 17 · Memory Blocks Tab Fields for Logical Block View](image)

The following figure shows the Memory Blocks tab fields for a physical block view.

![Figure 18 · Memory Blocks Tab Fields for Physical Block View](image)

Read Block
Memory blocks can be read once they are selected. If the block name appears on the right-hand side, the Read Block button is enabled. Click Read Block to read the memory block.
Logical Block Read
A logical block shows three fields. User Design Memory Block and Data Width are read only fields, and the Port Used field has options. If the design uses both ports, Port A and Port B are shown under options. If only one port is used, only that port is shown.

![Logical Block Read](image)

The data shown is in Hexadecimal format. In the example figure above, data width is 18. Because each hexadecimal character has 4 bits of information, you can see 5 characters corresponding to 18 bits. Each row has 16 locations (shown in the column headers) which are numbered in hexadecimal from 0 to F.

**Note:** For all logical blocks that cannot be inferred from physical blocks, the corresponding icon does not contain a letter.

Physical Block Read
When a Physical block is selected, only the User Design Memory Block and Data Width fields are shown.

![Physical Block Read](image)

Write Block

Logical Block write
A memory block write can be done on each location individually. A logical block has each location of width that is displayed. The written format is hexadecimal numbers from 0 to F. Width is shown in bits, and values
are shown in hexadecimal format. If an entered value exceeds the maximum value, SmartDebug displays a popup message showing the range of allowed values.

**Physical Block Write**

Physical blocks have a fixed width of 9 bits. The maximum value that can be written in hexadecimal format is 1FF. If an entered value exceeds the limit, SmartDebug displays a popup message showing the range of values that can be entered.

**Unsupported Memory Blocks**

If RTL is used to configure memory blocks, it is recommended that you follow RAM block inference guidelines provided by Microsemi. See [Inferring Microsemi SmartFusion2 RAM Blocks](#) for more information. SmartDebug may or may not be able to support logical view for memory blocks that are inferred using RTL coding not specified in the above document.

**Memory Blocks in Demo Mode**

A temporary memory data file is created in the designer folder for each type of RAM selected. All memory data of all instances of USRAM, LSRAM, and other RAM types is written to their respective data files. The default value of all memory locations is shown as 0s, and is updated based on your changes.
Both physical block view and logical block view are supported. See the following example figure.

Probe Insertion (Post-Layout) - SmartFusion2, IGLOO2, and RTG4

Introduction

Probe insertion is a post-layout debug process that enables internal nets in the FPGA design to be routed to unused I/Os. Nets are selected and assigned to probes using the Probe Insertion window in SmartDebug. The rerouted design can then be programmed into the FPGA, where an external logic analyzer or oscilloscope can be used to view the activity of the probed signal.

Note: This feature is not available in standalone mode because of the need to run incremental routing.
The Probe Insertion debug feature is complementary to Live Probes and Active Probes. Live Probes and Active Probes use a special dedicated probe circuitry.

**Probe Insertion**

1. Double-click **SmartDebug Design** in the Design Flow window to open the SmartDebug main window.  
   **Note:** FlashPro Programmer must be connected for SmartDebug.

2. Select **Debug FPGA Array** and then select the Probe Insertion tab.

   In the left pane of the Probe Insertion tab, all available Probe Points are listed in instance level hierarchy in the Hierarchical View. All Probe Names are shown with the Name and Type in the Netlist View.

3. Select probe points from the Hierarchical View or Netlist View, right-click and choose **Add** to add them to the Active Probes UI. You can also add the selected probe points by clicking the **Add** button. The probes list can be filtered with the Filter box.
Each entry has a Net and Driver name which identifies that probe point. The selected net(s) appear in the Probes table in the Probe Insertion tab, as shown in the figure below. SmartDebug automatically generates the Port Name for the probe. You can change the Port Name from the default if desired.

4. Assign a package pin to the probe using the drop-down list in the Package Pin column. You can assign the probe to any unused package pin (spare I/O).

![Figure 25 · Debug FPGA Array > Probe Insertion > Add Probe](image)

5. Click Run.

This triggers Place and Route in incremental mode, and the selected probe nets are routed to the selected package pin. After incremental Place and Route, Libero automatically reprograms the device with the added probes.

The log window shows the status of the Probe Insertion run.

**Probe Deletion**

To delete a probe, select the probe and click **Delete**. To delete all probes, click **Delete All**.

**Note**: Deleting probes from the probes list without clicking **Run** does not automatically remove the probes from the design.

**Reverting to the Original Design**

To revert to the original design after you have finished debugging:

1. In SmartDebug, click **Delete All** to delete all probes.
2. Click **Run**.
3. Wait until the action has completed by monitoring the activity indicator (spinning blue circle). Action is completed when the activity indicator disappears.
4. Close SmartDebug.
Event Counter

The Event Counter counts the signals that are assigned to Channel A through the Live Probe feature. This feature can track events from the MSS or the board. When the Event Counter is activated, and a signal is assigned to Channel A, the counter starts counting the rising edge transitions. The counter must be stopped to get the final signal transition count. During the count, you cannot assign another signal to Channel A/Channel B or go to any other tab on the window.

Activating the Event Counter

You can activate the Event Counter in either of the following two ways:

- Click **Activate Event Counter** and then assign a signal to Live Probe Channel A.
Figure 27 · Activating the Event Counter

- Assign a signal to Probe Channel A and then click **Activate Event Counter**.

Figure 28 · Activating the Event Counter - Assign Probe Channel
Running the Event Counter

Event Counter automatically runs the counter, which is indicated by a green LED. The counts are updated every second, and are shown next to Total Events. FPGA Array debug data and the control tabs in the Event Counter panel are disabled while Event Counter is running. When a signal is assigned, the signal name appears next to Signal.

![Figure 29 · Running the Event Counter](image)

Stopping the Event Counter

The only button enabled when Event Counter is running is the “Stop” button. Click button to stop counting. A red LED is shown to indicates the Event Counter has stopped. FPGA Array debug data and the control tabs in the Event Counter panel are enabled when Event Counter is not running.
Figure 30 · Stopping the Event Counter

Note: When a DC signal (signal tied to logic ‘0’) is assigned to Live Probe Channel A, or if there are no transitions on the signal assigned to Live Probe Channel A with initial state ‘0’, the Event Counter value is updated as ‘1’ when the counter is stopped. This is a limitation of the FHB IP, and will be fixed in upcoming releases.

See Also
“Frequency Monitor” on page 45
"User Clock Frequencies" on page 54

Frequency Monitor

The Frequency Monitor calculates the frequency of any signal in the design that can be assigned to Live Probe channel A. The Frequency Monitor must be activated before or after the signal is assigned to Live Probe Channel A. You can enter the time to monitor the signal. The accuracy of results increases as the monitor time increases. The unit of measurement is displayed in Megahertz (MHz). During the run, progress is displayed in the pane.
In the Frequency Monitor tab, you can activate the Frequency Monitor, change the monitor time (delay to calculate frequency), reset the monitor, and set the frequency in megahertz (MHz). Click the drop-down list to select monitor time value. During the frequency calculation, all tabs on the right side of the window are disabled, as well as the tabs in the FPGA Hardware Breakpoint (FHB) pane.

**Activating the Frequency Monitor**

You can activate the Frequency Monitor in either of the following two ways:

- Click **Activate Frequency Monitor**, and then click the **Live Probe** tab and assign a signal to Channel A (Channel B is not configured for spatial debug operations).
Figure 32 · Activating the Frequency Monitor - Assign a Signal

- Click the Live Probe tab and assign a signal to Channel A, and then click the Frequency Monitor tab and check the Activate Frequency Monitor checkbox.

Figure 33 · Activating the Frequency Monitor
Running the Frequency Monitor

The Frequency Monitor runs automatically, and is indicated by a green LED. While it is running, FPGA Array debug data and the control tabs in the panel are disabled. A progress bar shows the monitor time progress when it is 1 second and above (as shown in the following figure). The Reset button is also disabled during the run. When a signal is assigned, the signal name appears next to Signal.

![Figure 34 · Running the Frequency Monitor](image)

Stopping the Frequency Monitor

The Frequency Monitor stops when the specified monitor time has elapsed. This is indicated by a red LED. The result appears next to Frequency. The window and the tabs on the control panel are enabled. The Reset button is also enabled to reset the Frequency to 0 to start over the next iteration. The progress bar is hidden when the Frequency Monitor stops.
See Also

"Event Counter" on page 42
"User Clock Frequencies" on page 54

FPGA Hardware Breakpoint Auto Instantiation

The FPGA Hardware Breakpoint (FHB) Auto Instantiation feature automatically instantiates an FHB instance per clock domain that is using gated clocks (GL0/GL1/GL2/GL3) from an FCCC instance. The FHB instances gate the clock domain they are instantiated on. These instances can be used to force halt the design or halt the design through a live probe signal. Once a selected clock domain or all clock domains are halted, you can play or step on the clock domains, either selectively or all at once. The FPGA Hardware Breakpoint controls in the Smart Debug UI allow you to control the debugging cycle.

Note: This option is enabled in the Enhanced Constraint Flow when you select Verilog netlist as the Synthesis gate level netlist format in Project Settings (Project Settings > Design flow). It is only available for SmartFusion2 and IGLOO2 devices.

To enable this option, select the Enable FHB Auto Instantiation check box in the Design flow tab of the Project Settings dialog box (Libero > File > Project Settings). See the example figure that follows.
FPGA Hardware Breakpoint (FHB) controls appear in the Debug FPGA Array dialog box when there is an auto-instantiated FHB instance in the design. See the example figure that follows.

You can choose **Operate on All Clock Domains** or **Operate on Selected Clock Domain** by selecting the appropriate radio button. Selecting either of these modes sets the FHB instances to the respective mode. Once you assign the Live Probe PROBE_A connection and click **Arm Trigger**, the DUT halts on the next positive edge that occurs on the signal connected to Live Probe PROBE_A.
When you choose **Operate on Selected Clock Domain** mode, the Select Clock Domain combo box is enabled, and all available clock domains are listed. The Halt (Pause) \[\text{Pause}\], Play \[\text{Play}\], and Step buttons are associated for that clock domain. If you switch between clock domains in this mode, previous clock domain settings are not retained.

When you choose **Operate on All Clock Domains** mode, the Select Clock Domain combo box is disabled. The Halt, Play, and Step buttons are associated for all clock domains. The Trigger Signal is shown as Not Connected until a live probe is assigned. See the example figure that follows.

When a probe is assigned to Live Probe PROBE_A, the Trigger Signal updates. If you require a certain number of clock cycles before halting the clock domain after triggering, a value between 0 and 255 must be entered for Delay Cycles Before Halt before you click **Arm Trigger**. This sets the FHBs to trigger after the specified delay from the rising edge trigger.

Delay is not applied to a forced Halt. See the example figure that follows.
When a live probe connection is made, you click **Arm Trigger**, FPGA Hardware Breakpoint functionality is disabled until the trigger is disarmed automatically or the design is force halted.

Force Halt/Play/Step is done using the FPGA Hardware Breakpoint controls (see the example figure that follows). Once the clock domain is halted, you can either force Play the clock domain or Step the clock domain by 1 clock cycle.
You can save the waveform view of the selected active probes using Export Waveform by specifying the number of clock cycles to capture. The waveform is saved to a .vcd file.

FPGA Hardware Breakpoint Operations

**Live Probe Halt**

You can halt a selected clock domain or all clock domains in Live Probe Halt mode based on the mode selection (Operate on All Clock Domains or Operate on Selected Clock Domain).

Assign a signal to Live Probe PROBE_A in the Live Probes tab of the UI, and then click the Active Probe tab to see the FPGA Hardware Breakpoint controls.

Click **Arm Trigger** to arm the FHBs to look for a trigger on the signal connected to Live Probe PROBE_A. Once the trigger occurs, the clock domains are halted.

**Note:** If only one clock domain is halted, other clock domains continue to run, and you should anticipate results accordingly.

See Assumptions and Limitations for more information.

**Force Halt**

You can force halt a selected clock domain or all clock domains based on mode selection without having to wait for a trigger from a live probe signal. Click the **Halt** button in the FPGA Hardware Breakpoint (FHB) controls.

In **Operate on Selected Clock Domain** mode, the state of the Halt button is updated based on the state of the clock domain selected.

In **Operate on all Clock Domains** mode, the Halt button is disabled only when all clock domains are halted. Each clock domain is halted sequentially in the order shown in the Select Clock Domain combo box.

**Note:** If only one clock domain is halted, other clock domains continue to run, and you should anticipate results accordingly.
Play
Once the clock domain is in a halted state (live probe halt or force halt), you can click Play in the FPGA Hardware Breakpoint controls. This resumes the clock domain from the halted state.

In Operate on all Clock Domains mode, each clock domain runs sequentially in the order shown in the Select Clock Domain combo box.

Step
Once the clock domain is in a halted state (live probe halt or force halt), you can click the Step button in the FPGA Hardware Breakpoint controls. This advances the clock domain by one clock cycle and holds the state of the clock domain.

In Operate on All Clock Domains mode, each clock domain steps sequentially in the order shown in the Select Clock Domain combo box.

Waveform Capture
You can save the waveform view of the selected active probes using Export Waveform by specifying the number of clock cycles to capture in text box and then clicking Capture Waveform. The waveform is saved to a .vcd file.

You can view the waveforms by importing the .vcd file. The waveform file can be viewed in any waveform viewer that supports vcd format.

Reset
You can reset a selected clock domain or all clock domains (based on the mode selection) by clicking RESET at any time. This resets the FHBs on clock domains and instructs FHB muxes not to look for a trigger.

Assumptions and Limitations
- If you select the auto instantiation option in Libero, you need to rerun Synthesis (if already run) to get the FHB related functionality.
- The auto instantiation flow is supported for SmartFusion2 and IGLOO2 only.
- Available for Enhanced Constraint Flow only.
- Supported for FCC driven gated clocks (GL0/GL1/GL2/GL3) only.
- CLKINT_PRECLUDE – FHB is not auto-instantiated if the user design contains this macro.
- Designs that have Encrypted IPs are not supported.
- EDIF using constraints flow is not supported.
- Live Probe triggering occurs on the Positive Edge only.
- For imported verilog netlist files (.vm files), you must rerun synthesis to get FHB-related functionality. If synthesis is disabled and the netlist is compiled directly, FHB functionality is not inferred.
- If only one clock domain is halted during operations, other clock domains continue to run, and you should anticipate results accordingly.
- FHB performance can only be characterized against the clock which it is running at (i.e. 50MHz).
  - If the DUT clock is running at or less than 50MHz, the DUT clock will halt within one clock cycle (1 or less).
  - For frequencies higher than 50MHz, the point at which the DUT halts cannot be guaranteed.

User Clock Frequencies
The User Clock Frequencies tab shows the frequencies that have been configured from the FCCC block. If assigned, live probe channels are temporarily unassigned, and reassigned after user clock frequencies have been calculated. The Refresh button recalculates frequencies if clocks have been changed.
Pseudo Static Signal Polling

With Active Probes you can check the current state of any probe in the design. However, in most cases, you
will not able to time the active probe read to capture its intended value. For these cases, you can use
Pseudo Static Signal Polling, in which the SmartDebug software polls the signal at intervals of one second to
check if the probe has the intended value. This feature is useful in probing signals which reach the intended
state and stay in that state.

From the Active Probes tab in the Debug FPGA Array dialog box, right-click a signal, bus, or group and
choose Poll.... See the example figure that follows.

See Also

"Event Counter" on page 42
"Frequency Monitor" on page 45

UG0449- SmartFusion2 and IGLOO2 Clocking Resources User Guide
UG0586- RTG4 FPGA Clocking Resources User Guide
The Pseudo-static signal polling dialog box opens.

**Scalar Signal Polling**

**Polling Setup**

To poll scalar signals, select **Poll for 0** or **Poll for 1**.

The selected signal is polled once per second. It should be used for pseudo-static signals that do not change frequently. The elapsed time is shown next to **Time Elapsed in seconds**.

To begin polling, click **Start Polling**. See the following example figure.

To end polling, click **Stop Polling**. See the following example figure.
Figure 41 · Pseudo-static signal polling Dialog Box (Scalar Signal Polling) - Stop Polling

**Note:** You cannot change the poll value or close the polling dialog box while polling is in progress. The elapsed time is updated in seconds until the polled value is found. When the polled value is found, **User value matched** is displayed in green in the dialog box. See the following example figure.

Figure 42 · Pseudo-static signal polling Dialog Box (Scalar Signal Polling) - User Value matched

**Vector Signal Polling**

To poll vector signals, enter a value in the text box. The entered value is checked and validated. If an invalid value is entered, start polling is disabled, and an example displays showing the required format. See the following example figures.
When you enter a valid value and click **Start Polling** is clicked, polling begins.
To end polling, click **Stop Polling**.

**Note:** You cannot change the poll value or close the polling dialog box while polling is in progress.
The elapsed time is updated in seconds until the polled value is found. When the polled value is found, **User value matched** is displayed in green in the dialog box.

**Debug SERDES (SmartFusion2, IGLOO2, and RTG4)**

You can examine and debug the SERDES blocks in your design in the Debug SERDES dialog box (shown in the figure below).
To Debug SERDES, expand **SmartDebug** in the Design Flow window and double-click **Debug SERDES**. Debug SERDES Configuration is explained below. See the **PRBS Test** and **Loopback Test** topics for information specific to those procedures.

**SERDES Block** identifies which SERDES block you are configuring. Use the drop-down menu to select from the list of SERDES blocks in your design.

### Debug SERDES - Configuration

#### Configuration Report

The Configuration Report output depends on the options you select in your **PRBS Test** and **Loopback Tests**. The default report lists the following for each Lane in your SERDES block:

- **Lane mode** - Indicates the programmed mode on a SERDES lane as defined by the SERDES system register.
- **PMA Ready** - Indicates whether PMA has completed its internal calibration sequence for the specific lane and whether the PMA is operational. See the **SmartFusion2** or **IGLOO2** High Speed Serial Interfaces User Guide on the Microsemi website for details.
- **TxPLL status** - Indicates the loss-of-lock status for the TXPLL is asserted and remains asserted until the PLL reacquires lock.
- **RxPLL status** - Indicates the CDR PLL frequency is not grossly out of range of with incoming data stream.

Click **Refresh Report** to update the contents of your SERDES Configuration Report. Changes to the specified SERDES register programming can be read back to the report.

#### SERDES Register Read or Write

- **Script** - Runs Read/Write commands to access the SERDES control/status register map using a script. Enter the full pathname for the script location or click the browse button to navigate to your script file. Click **Execute** to run the script.
Figure 45 · Debug SERDES - Configuration

Note: The PCIe and XAUI protocols only support PRBS7. The EPCS protocol supports PRBS7/11/23/31.

Debug SERDES – Loopback Test

Loopback data stream patterns are generated and checked by the internal SERDES block. These are used to self-test signal integrity of the device. You can switch the device through predefined tests.

See the PRBS Test topic for more information about the PRBS test options. SERDES Block identifies which SERDES block you are configuring. Use the drop-down menu to select from the list of SERDES blocks in your design.

SERDES Lanes

Select the Lane and Lane Status on which to run the Loopback test. Lane mode indicates the programmed mode on a SERDES lane as defined by the SERDES system register.

Test Type

PCS Far End PMA RX to TX Loopback - This loopback brings data into the device and deserializes and serializes the data before sending it off-chip. This loopback requires 0PPM clock variation between the TX and RX SERDES clocks.

See the SmartFusion2 or IGLOO2 High Speed Serial Interfaces User’s Guide on the Microsemi website for details.

Near End Loopback (On Die) - To enable, select the Near End Loopback (On Die) option and click Start. Click Stop to disable. Using this option allows you to send and receive user data without sending traffic off-chip. You can test design functionality without introducing other issues on the PCB.
See the SmartFusion2 or IGLOO2 High Speed Serial Interfaces User's Guide on the Microsemi website for details.

Running Loopback Tests in Demo Mode

You can run Loopback tests in demo mode. The SERDES demo mode is provided to demonstrate the GUI features of SERDES. All channels are enabled. Properly working channels and channels with connectivity issues are shown so you can see the available GUI options. See the following example figure.
Debug SERDES – PRBS Test

PRBS data stream patterns are generated and checked by the internal SERDES block. These are used to self-test signal integrity of the device. You can switch the device through several predefined patterns. View Loopback Test settings in the Debug SERDES - Loopback Test topic.

**SERDES Block** identifies which SERDES block you are configuring. Use the drop-down menu to select from the list of SERDES blocks in your design.

**SERDES Lanes**

Check the box or boxes to select the lane(s) on which to run the PRBS test. Then select the Lane Status, test type, and pattern for each lane you have selected. Lane mode indicates the programmed mode on a SERDES lane as defined by the SERDES system register. See the examples below.
Figure 47 · SERDES Lanes - Single Lane Selected

Figure 48 · SERDES Lanes - Multiple Lanes Selected
**Test Type**

Near End Serial Loopback (On-Die) enables a self-test of the device. The serial data stream is sent internally from the SERDES TX output and folded back onto the SERDES RX input.

Serial Data (Off-Die) is the normal system operation where the data stream is sent off chip from the TX output and must be connected to the RX input via a cable or other type of electrical interconnection.

If more than one SERDES Lane has been selected, the test type can be selected per lane. In the following example, Near End Serial Loopback (On-Die) has been selected for Lane 0 and Lane 3, and Serial Data (Off-Die) has been selected for Lane 1 and Lane 2.

![Figure 49 · Test Type Example](image)

**Pattern**

The SERDESIF includes an embedded test pattern generator and checker used to perform serial diagnostics on the serial channel, as shown in the table below. If more than one lane is selected, the PRBS pattern can be selected per lane.

<table>
<thead>
<tr>
<th>Pattern</th>
<th>Type</th>
</tr>
</thead>
<tbody>
<tr>
<td>PRBS7</td>
<td>Pseudo-Random data stream of 2^7 polynomial sequences</td>
</tr>
<tr>
<td>PRBS11</td>
<td>Pseudo-Random data stream of 2^11 polynomial sequences</td>
</tr>
<tr>
<td>PRBS23</td>
<td>Pseudo-Random data stream of 2^23 polynomial sequences</td>
</tr>
<tr>
<td>PRBS31</td>
<td>Pseudo-Random data stream of 2^31 polynomial sequences</td>
</tr>
</tbody>
</table>
**Cumulative Error Count**

Lists the number of cumulative errors after running your PRBS test. To reset the error count to zero, select the lane(s) and click **Reset**. By default, Cumulative Error Count = 0, the Data Rate text box is blank, and Bit Error Rate = NA.

![Debug SERDES - PRBS Test](image)

**Figure 50 · Debug SERDES - PRBS Test**

**Note**: If the design uses SERDES PCIe, PRBS7 is the only available option for PRBS tests.

**Bit Error Rate**

The Bit Error Rate is displayed per lane. If you did not specify a Data Rate, the Bit Error Rate displays the default NA. When the PRBS test is started, the Cumulative Error Count and Bit Error Rate are updated every second. You can select specific lanes and click **Reset Error Count** to clear the Cumulative Error Count and Bit Error Rate fields of the selected lanes.

In the example below, the Bit Error Rate is displayed for all lanes.
In the example below, Lane 1 and Lane 2 are selected and **Reset Error Count** is clicked.
Running PRBS Tests in Demo Mode

You can run Multi Lane PRBS tests in demo mode. The SERDES demo mode is provided to demonstrate the GUI features of SERDES. All channels are enabled. Properly working channels and channels with connectivity issues are shown so you can see the available GUI options. See the following example figure.

Notes:
The formula for calculating the BER is as follows:

\[ BER = \frac{\text{#bit errors} + 1}{\text{bits sent}} \]

\[ \text{bits sent} = \frac{\text{Elapsed time}}{\text{bit period}} \]

When clicked on Start:
- The BER is updated every second for the entered data rate and errors observed.
- If no data rate is entered by the user, the BER is set to the default NA.

When clicked on Stop:
- The BER resets to default.

When clicked on Reset:
- The BER resets to default.
- If no test is in progress, the BER remains in the default value.
- If the PRBS test is in progress, the BER calculation restarts.

Debug SERDES – PHY Reset

SERDES PMA registers (for example, TX_AMP_RATIO) modified using a TCL script from the Configuration tab require a soft reset for the new values to be updated. Lane Reset for individual lanes achieves this functionality. Depending on the SERDES lanes used in the design, the corresponding Lane Reset buttons are enabled.

Lane Reset Behavior for SERDES Protocols Used in the Design
- EPCS: Reset is independent for individual lanes. Reset to Lane X (where X = 0,1,2,3) resets the Xth lane.
- PCIe: Reset to Lane X (where X = 0,1,2,3) resets all lanes present in the PCIe link and PCIe controller. For more information about soft reset, refer to the SmartFusion2 and IGLOO2 High Speed Serial Interfaces User Guide.

Device Status Report (SmartFusion and Fusion Only)

This dialog box displays the Device Information report. The Device Information report is a complete summary of your device state, analog block test values, user information, factory serial number, and security information. Use this dialog box to save or print your information for future reference.

![Device Status Report](image)

Figure 53 · Device Status Report
Inspect Device Dialog Box (SmartFusion, Fusion, and ProASIC3 Only)

Inspect Device is available as a part of the FlashPro programming tool. Refer to Using SmartDebug for information about how to configure FlashPro to access this feature.

In the Inspect Device dialog box, you can access all device features, such as the FlashROM, Embedded Flash Memory (NVM), and Analog Block. If you have multiple devices and programmers connected, choose your target device/programmer from the drop-down menu, and use the ID code to verify that you are inspecting the correct device.

**View Device Status** - Displays the Device Status Report. The Device Status Report is a summary of your device state, analog block test values, user information, factory data, and security information. You can save or print your information for future reference.

**View Analog Block Configuration** - Opens the Analog Block Configuration dialog box. You can view the channel configuration for your analog block and compare the channel configuration with any other analog block file.

**View Flash Memory Content** - Opens the Flash Memory dialog box. You can view the details for each flash memory block in your device.

**View FlashROM Content** - Opens the FlashROM data dialog box. You can view a list of the physical blocks in your FlashROM and the client partitions in FlashROM configuration files.

![Inspect Device Dialog Box](image)

Figure 54 · Inspect Device Dialog Box

Embedded Flash Memory (NVM) Content Dialog Box (SmartFusion and Fusion Only)

You can do the following in the NVM content dialog box:

- View content of Flash Memory pages (as shown in the figure below)
- Compare device content with original design content (requires a PDB that contains your EFC data)
- Check page status and identify if a page is corrupted or if the write count limit has exceeded the 10-year retention threshold

**Fusion Devices**: Choose your block from the From block drop-down list. This action populates the Select drop-down list with the names of the clients in the selected block that is configured in the Flash Memory System Builder.

**SmartFusion Devices**: Block selection is unused and unavailable.

Choose a client name from the Select drop-down list and click Read from Device to view the values. You can also view a specific page range by selecting the <Page Range> option in the Select drop-down list and then specifying the start page and the end page.
You must click **Read from Device** each time you specify a new page range to update the view.

If you do not have your original design programming database (PDB) file, you can examine and retrieve a range of pages. Specify a page range if you wish to examine a specific set of pages. Page Status information appears to the right.

![Flash Memory Content Dialog Box for a SmartFusion Device (SmartDebug)](image)

**Figure 55 · Flash Memory Content Dialog Box for a SmartFusion Device (SmartDebug)**

**Embedded Flash Memory: Browse Retrieved Data (SmartFusion and Fusion Only)**

The retrieved data table displays the content of the selected client or the page range selection. Corrupted page content is displayed in red. Read-only page content, corresponding to clients defined with the Prevent read option in Flash Memory System Builder, is displayed with a gray background. If content cannot be read (for example, pages are read-protected, but security has been erased), the content is displayed as XX. The mouse tooltip summarizes abnormal content status (as shown in the figure below).

The corresponding page number and address (relative to the current block) are displayed in the left column. The client size specified in the Flash Memory System Builder is shown at the top of the content table.

In the Retrieved Data View, you can enter an Address value (such as 0010) in the Go to Address field and click the corresponding button to go directly to that address.

Click **View Detailed Status** for a detailed report on the page range you have selected.

For example, if you want to view a report on pages 1-3, set the **Start Page** to 1, set the **End Page** to 3, and click **Read from Device**. Then click **View Detailed Status**. The figure below is an example of the data for a specific page range.
Figure 56 · Flash Memory Details Dialog Box (SmartDebug)

Figure 57 · Flash Memory Browse Retrieved Data
Embedded Flash Memory: Compare Memory Client (SmartFusion and Fusion Only)

After you retrieve the data from the device, the Compare Client Content button lets you compare the content of the selected client from the device with the original programming database (PDB) file. The differences are shown in the Compare Memory Client dialog box (as shown in the figure below).

**Note:** This option is not available when you select to retrieve the data based on a page range.

![Compare Memory Client Dialog Box](image)

FlashROM Content Dialog Box (Fusion and SmartFusion Only)

In the FlashROM Content dialog box, you can view the physical blocks in your FlashROM and the client partitions specified in the original design content (requires a PDB that contains your UFC data). If the project's PDB does not contain UFC data, only the physical blocks are displayed.

Scroll through the table to view the Words and Pages for your physical blocks.

The Client Partitions section lists the names and configuration details of the clients set up in the FlashROM Builder. It automatically finds all mismatched client regions. To view the differences between a client and the device content, select a region row in the Client Partitions table. This action highlights the corresponding device content in the Physical Blocks table. The mismatch details are displayed below the Client Partitions table.

To copy the content of the Physical Blocks table to clipboard, select one or more cells in the table and type Ctrl+C.
In the Analog Block Configuration dialog box, you can:

- View the channel configuration on your analog system and identify if/how the channels are configured.
- Compare with the design configuration from the Analog System Builder for Fusion and SmartDesign MSS Configurator for SmartFusion.

The values displayed for each channel vary depending on the device family and channel you select; the Channel configuration register read from the ACM is shown for each analog channel. Individual, decoded bit fields of the register are listed immediately beneath (as described in the Fusion and SmartFusion handbook). The dialog box may display the following values:

**Fusion Device:**
- Analog MUX select
- Internal chip T monitor
- Scaling factor control
- Current monitor switch
- Current monitor drive control
- Direct analog input switch
- Pad polarity - G, T, V, C pad polarity, positive or negative
- Select low/high drive
- Prescaler op amp mode

**SmartFusion Device:**
- Gain select
- Channel state
- Direct Input state
- Current Monitor state
- Current monitor strobe state
- Comparator state
- Hysteresis select
- Analog MUX select
- DAC input select
- Temperature monitor state
- Temperature monitor strobe state
- Vref switch state

To use the compare feature, select the **Compare with** checkbox. If the loaded PDB file contains Analog Block configuration information, the comparison appears automatically.

To use a specific Project File, click **Browse** and navigate to the Analog System Builder directory for Fusion or SmartDesign for SmartFusion. In a typical IDE project, this directory is located at:

- Fusion - `<project_root>/smartgen/<analog_block_core_name>`
- SmartFusion - `<project root>/component/work/<SmartDesign project>/MSS_ACE_0`

After specifying the compare directory, the differences (if any) are indicated in red on a channel by channel basis, as shown in the figure below.
### Analog Block Configuration Dialog Box for a Fusion Device (Differences in Red)

<table>
<thead>
<tr>
<th>Channel</th>
<th>Byte</th>
<th>Device Content</th>
<th>File Content</th>
</tr>
</thead>
<tbody>
<tr>
<td>AV0</td>
<td>0x81</td>
<td>0x81</td>
<td>0x38</td>
</tr>
<tr>
<td>ACO</td>
<td>0x00</td>
<td>Prescaler</td>
<td>Direct Input</td>
</tr>
<tr>
<td>AQ0</td>
<td>0x00</td>
<td>0.3125 (V)</td>
<td>0.15525 (16V)</td>
</tr>
<tr>
<td>ATO</td>
<td>0x80</td>
<td>Off</td>
<td>On</td>
</tr>
<tr>
<td>AV1</td>
<td>0x92</td>
<td>Off</td>
<td>On</td>
</tr>
<tr>
<td>AC1</td>
<td>0x10</td>
<td>Positive</td>
<td>Positive</td>
</tr>
<tr>
<td>AG1</td>
<td>0x00</td>
<td>Operational</td>
<td>Powerdown</td>
</tr>
<tr>
<td>AT1</td>
<td>0x80</td>
<td></td>
<td></td>
</tr>
<tr>
<td>AV2</td>
<td>0x92</td>
<td></td>
<td></td>
</tr>
<tr>
<td>AC2</td>
<td>0x10</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Figure 60** - Analog Block Configuration Dialog Box for a Fusion Device (Differences in Red)
## SmartDebug Tcl Commands

### SmartDebug Tcl Support (SmartFusion2, IGLOO2, and RTG4)

The following table lists the Tcl commands related to SmartDebug for SmartFusion2, IGLOO2, and RTG4. Click the command to view more information.

<table>
<thead>
<tr>
<th>Command</th>
<th>Action</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>DDR/MDDR</strong></td>
<td></td>
</tr>
<tr>
<td><strong>ddr_read</strong></td>
<td>Reads the value of specified configuration registers pertaining to the DDR memory controller (MDDR/FDDR)</td>
</tr>
<tr>
<td><strong>ddr_write</strong></td>
<td>Writes the value of specified configuration registers pertaining to the DDR memory controller (MDDR/FDDR)</td>
</tr>
<tr>
<td><strong>Probe</strong></td>
<td></td>
</tr>
<tr>
<td><strong>add_probe_insertion_point</strong></td>
<td>Adds probe points to be connected to user-specified I/Os for probe insertion flow.</td>
</tr>
<tr>
<td><strong>add_to_probe_group</strong></td>
<td>Adds the specified probe points to the specified probe group</td>
</tr>
<tr>
<td><strong>create_probe_group</strong></td>
<td>Creates a new probe group.</td>
</tr>
<tr>
<td><strong>delete_active_probe</strong></td>
<td>Deletes either all or the selected active probes.</td>
</tr>
<tr>
<td><strong>load_active_probe_list</strong></td>
<td>Loads the list of probes from the file.</td>
</tr>
<tr>
<td><strong>move_to_probe_group</strong></td>
<td>Moves the specified probe points to the specified probe group.</td>
</tr>
<tr>
<td><strong>program_probe_insertion</strong></td>
<td>Runs the probe insertion flow on the selected nets.</td>
</tr>
<tr>
<td><strong>remove_probe_insertion_point</strong></td>
<td>Deletes an added probe from the probe insertion UI.</td>
</tr>
<tr>
<td><strong>set_live_probe</strong></td>
<td>Set Live probe channels A and/or B to the specified probe point (or points).</td>
</tr>
<tr>
<td><strong>select_active_probe</strong></td>
<td>Manages the current selection of active probe points to be used by active probe READ operations.</td>
</tr>
<tr>
<td><strong>read_active_probe</strong></td>
<td>Reads active probe values from the device.</td>
</tr>
<tr>
<td><strong>remove_from_probe_group</strong></td>
<td>Move out the specified probe points from the group.</td>
</tr>
<tr>
<td><strong>save_active_probe_list</strong></td>
<td>Saves the list of active probes to a file.</td>
</tr>
<tr>
<td><strong>select_active_probe</strong></td>
<td>Manages the current selection of active probe points to be used by active probe READ operations.</td>
</tr>
<tr>
<td><strong>ungroup</strong></td>
<td>Disassociates the probes as group.</td>
</tr>
<tr>
<td>Command</td>
<td>Action</td>
</tr>
<tr>
<td>--------------------</td>
<td>------------------------------------------------------------------------</td>
</tr>
<tr>
<td><strong>DDR/MDDR</strong></td>
<td></td>
</tr>
<tr>
<td>unset_live_probe</td>
<td>Discontinues the debug function and clears live probe channels.</td>
</tr>
<tr>
<td>write_active_probe</td>
<td>Sets the target probe point on the device to the specified value.</td>
</tr>
<tr>
<td><strong>LSRAM</strong></td>
<td></td>
</tr>
<tr>
<td>read_lsramp</td>
<td>Reads a specified block of large SRAM from the device.</td>
</tr>
<tr>
<td>write_lsramp</td>
<td>Writes a seven bit word into the specified large SRAM location.</td>
</tr>
<tr>
<td><strong>uSRAM</strong></td>
<td></td>
</tr>
<tr>
<td>read_usram</td>
<td>Reads a uSRAM block from the device.</td>
</tr>
<tr>
<td>write_usram</td>
<td>Writes a seven bit word into the specified uSRAM location.</td>
</tr>
<tr>
<td><strong>SERDES</strong></td>
<td></td>
</tr>
<tr>
<td>loopback_test</td>
<td>Starts and stops the loopback tests.</td>
</tr>
<tr>
<td>serdes_lane_reset</td>
<td>In EPCS mode, this command resets the lane. In PCI mode, this command</td>
</tr>
<tr>
<td></td>
<td>resets the lane, all other lanes in the link, and the corresponding</td>
</tr>
<tr>
<td></td>
<td>PCIe controller.</td>
</tr>
<tr>
<td>serdes_read_register</td>
<td>Reads the SERDES register value and displays the result in the log</td>
</tr>
<tr>
<td></td>
<td>window/console.</td>
</tr>
<tr>
<td>serdes_write_register</td>
<td>Writes the value to the SERDES register.</td>
</tr>
<tr>
<td><strong>Additional Commands</strong></td>
<td></td>
</tr>
<tr>
<td>event_counter</td>
<td>Runs on signals that are assigned to channel A on the live probe, and</td>
</tr>
<tr>
<td></td>
<td>displays the total events.</td>
</tr>
<tr>
<td>export_smart_debug_data</td>
<td>Exports debug data for the SmartDebug application.</td>
</tr>
<tr>
<td>fhb_control</td>
<td>Provides FPGA Hardware Breakpoint (FHB) feature capability for SmartDebug.</td>
</tr>
<tr>
<td>frequency_monitor</td>
<td>Calculates the frequency of a signal that is assigned to live probe A.</td>
</tr>
<tr>
<td>get_programmer_info</td>
<td>Lists the IDs of all FlashPRO programmers connected to the machine.</td>
</tr>
</tbody>
</table>
Device Debug / SmartDebug Tcl Commands (SmartFusion, IGLOO, ProASIC3, and Fusion Only)

Note: Tcl commands in this section may not be supported by all device families listed above. See the individual commands for specific device support.

The following table lists the Tcl commands related to Device Debug / SmartDebug for SmartFusion and Fusion). Click the command to view more information.

<table>
<thead>
<tr>
<th>Command</th>
<th>Action</th>
<th>Type</th>
</tr>
</thead>
<tbody>
<tr>
<td>check_flash_memory</td>
<td>Performs diagnostics of the page status and data information.</td>
<td>Embedded Flash Memory (NVM)</td>
</tr>
<tr>
<td>compare_analog_config</td>
<td>Compares the content of the analog block configurations in your design against the actual values in the device.</td>
<td>Analog Block</td>
</tr>
<tr>
<td>compare_flashrom_client</td>
<td>Compares the content of the FlashROM configurations in your design against the actual values in the selected device.</td>
<td>FlashROM</td>
</tr>
<tr>
<td>compare_memory_client</td>
<td>Compares the memory client in a specific device and block.</td>
<td>Embedded Flash Memory (NVM)</td>
</tr>
<tr>
<td>read_analog_block_config</td>
<td>Reads each channel configuration on your analog system, enabling you to identify if/how each channel is configured.</td>
<td>Analog Block</td>
</tr>
<tr>
<td>read_device_status</td>
<td>Displays a summary of the selected device.</td>
<td></td>
</tr>
<tr>
<td>read_flashrom</td>
<td>Reads the content of the FlashROM from the selected device.</td>
<td>FlashROM</td>
</tr>
<tr>
<td>read_flash_memory</td>
<td>Reads information from the NVM modules (page status and page data).</td>
<td>Embedded Flash Memory (NVM)</td>
</tr>
<tr>
<td>read_id_code</td>
<td>Reads IDCode from the device without masking any IDCode fields.</td>
<td></td>
</tr>
<tr>
<td>recover_flash_memory</td>
<td>Removes ECC2 errors due to memory corruption by reprogramming specified flash memory (NVM) pages and initializing all pages to zeros.</td>
<td>Embedded Flash Memory (NVM)</td>
</tr>
<tr>
<td>sample_analog_channel</td>
<td>Samples analog channel; enables you to debug ADC conversion of the preconfigured analog channel (you must provide ADC conversion parameters).</td>
<td></td>
</tr>
<tr>
<td>set_debug_device</td>
<td>Identifies the device you intend to debug.</td>
<td></td>
</tr>
<tr>
<td>set_debug_programmer</td>
<td>Identifies the programmer you want to use for debugging (if you have more than one).</td>
<td></td>
</tr>
</tbody>
</table>
add_probe_insertion_point
This Tcl command adds probe points to be connected to user-specified I/Os for probe insertion flow.

```
add_probe_insertion_point -net net_name -driver driver -pin package_pin_name -port port name
```

**Arguments**
- **-net net_name**
  Name of the net used for probe insertion.
- **-driver driver**
  Driver of the net.
- **-pin package_pin_name**
  Package pin name (i.e. I/O to which the net will be routed during probe insertion).
- **-port port_name**
  User-specified name for the probe insertion point.

**Supported Families**
SmartFusion2, IGLOO2, RTG4

**Example**
```
add_probe_insertion_point -net {count_out_c[0]} -driver {Counter_8bit_0_count_out[0]:Q} -pin {H5} -port {Probe_Insert0}
```

add_to_probe_group
Tcl command; adds the specified probe points to the specified probe group.

```
add_to_probe_group -name probe_name -group group_name
```

**Arguments**
- **-name probe_name**
  Specifies one or more probes to add.
- **-group group_name**
  Specifies name of the probe group.

**Supported Families**
SmartFusion2, IGLOO2, and RTG4

**Example**
```
add_to_probe_group -name out[5]:out[5]:Q \ 
   -name grp1.out[3]:out[3]:Q \ 
   -name out.out[1].out[1]:Q \ 
   -group my_new_grp
```

check_flash_memory
The command performs diagnostics of the page status and data information as follows:
- Page Status – includes ECC2 check of the page status information, write count
- Page Data - ECC2 check
check_flash_memory
[-name {device_name}]
[-block {integer_value}]
[-client {client_name}]
[-startpage {integer_value}]
[-endpage {integer_value}]
[-access {all | status | data}]
[-show {summary | pages}]
[-file {filename}]

At a minimum you must specify -client <name> OR
- startpage <page_number> -endpage <page_number> -block <number>

Arguments

-name {device_name}
Optional user-defined device name. The device name is not required if there is only one device in the
current configuration, or a device has already been selected using the set_debug_device command.

-block {integer_value}
(Optional argument; you must set -client or -startpage, -endpage and -block before use.) Specifies
location of block for memory check.

-client {client_name}
Name of client for memory check.

-startpage {integer_value}
Startpage for page range; value must be an integer. You must specify a -endpage and -block along with
this argument.

-endpage {integer_value}
Endpage for page range; value must be an integer. You must specify a -startpage and -block along with
this argument.

-access {all | status | data}
(Optional argument; you must set -client or -startpage, -endpage and -block before use.) Specifies what
NVM information to check: page status, data or both.

<table>
<thead>
<tr>
<th>Value</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>all</td>
<td>Shows the number of pages with corruption status, data corruption and out-of-range write count (default)</td>
</tr>
<tr>
<td>status</td>
<td>Shows the number of pages with corruption status and the number of pages with out-of-range write count</td>
</tr>
<tr>
<td>data</td>
<td>Shows only the number of pages with data corruption</td>
</tr>
</tbody>
</table>

-show {summary | pages}
(Optional argument; you must set -client or -startpage, -endpage and -block before use.) Specifies
output level, as explained in the table below.

<table>
<thead>
<tr>
<th>Value</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>summary</td>
<td>Displays the summary for all checked pages (default)</td>
</tr>
<tr>
<td>pages</td>
<td>Displays the check results for each checked page</td>
</tr>
</tbody>
</table>

-file {filename}
(Optional argument; you must set -client or -startpage, -endpage and -block before use.) Name of output file for memory check.

**Supported Families**

SmartFusion, Fusion

**Exceptions**

None

**Example**

The following command checks the page status for block 0 from starpage 0 to endpage 2:

```
check_flash_memory -startpage 0 -endpage 2 -block 0
```

The following command checks the memory status for the client 'DS8bit' and saves it to the file 'checkFlashMemory.log':

```
check_flash_memory -client {DS8bit} -file {checkFlashMemory.log}
```

**compare_analog_config**

Compares the content of the analog block configurations in your design against the actual values in the device. In a typical SoC project, this directory is located at `<project_root>/smartgen/<analog_block_core_name>`.

```
compare_analog_config
[-name "device_name"] -mem_file_dir "mem_file_directory"
[-file "filename"]
```

**Arguments**

- **-name (device_name)**
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the set_debug_device command.

- **-mem_file_dir {mem_file_directory}**
  Location of memory file.

- **-file {filename}**
  Output filename.

**Supported Families**

Fusion

**Exceptions**

None

**Example**

The following command reads the analog block configuration in the directory F:/tmp/Analog_Block and saves the data in the logfile compare_analogReport.log:

```
compare_analog_config -mem_file_dir {F:/tmp/Analog_Block} -file {compare_analogReport.log}
```

The following command reads the analog block configuration information in the device 'AFS600' in the directory F:/tmp/Analog_Block and saves the data in the log file compare_analogReport.log:

```
compare_analog_config –name {AFS600} -mem_file_dir {F:/tmp/Analog_Block} -file {compare_analogReport.log}
```
Note: If an absolute path is not entered, the log file is saved in the directory in which the Tcl script was executed in SmartDebug.

**compare_flashrom_client**

Compares the content of the FlashROM configurations in your design against the actual values in the selected device.

```
compare_flashrom_client [-name {device_name}] [-file {filename}]
```

**Arguments**

- `-name {device_name}`
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.
- `-file {filename}`
  Optional file name for FlashROM compare log.

**Supported Families**

SmartFusion, IGLOO, ProASIC3 and Fusion

**Exceptions**

None

**Example**

The following command saves the FlashROM data to the file 'FlashRomCompReport.log':

```
compare_flashrom_client -file {FlashRomCompReport.log}
```

The following command compares the data in the device 'A3P250' and saves the data in the logfile 'FlashRomCompReport.log':

```
compare_flashrom_client -name {A3P250} -file {FlashRomCompReport.log}
```

Note: If an absolute path is not entered, the log file is saved in the directory in which the Tcl script was executed in SmartDebug.

**compare_memory_client**

Compares the memory client in a specific device and block.

```
compare_memory_client [-name {device_name}] [-block integer_value] -client {client_name} [-file {filename}]
```

**Arguments**

- `-name {device_name}`
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.
- `-block {integer_value}`
  (Optional argument; you must set -client.) Specifies location of block for memory compare.
- `-client {client_name}`
  Name of client for memory compare.
- `-file {filename}`
  Optional file name.
Supported Families

SmartFusion and Fusion

Exceptions

None

Example

The following command compares the memory in the client 'DS32' on the device 'AFS600'.

```
compare_memory_client -client DS32 -name AFS600
```

The following command compares the data at block '0' to the client 'DS8bit':

```
compare_memory_client -block 0 -client {DS8bit}
```

The following command compares the memory in the device 'AFS600' at block '0' to the memory client 'DS8bit':

```
compare_memory_client -name {AFS600} -block 0 -client {DS8bit}
```

The following command compares the memory at block '1' to the memory client 'DS8bit' and saves the information in a log file to F:/tmp/NVMCompReport.log:

```
compare_memory_client -block 1 -client {DS8bit} -file {F:/tmp/NVMCompReport.log}
```

create_probe_group

Tcl command; creates a new probe group.

```
create_probe_group -name group_name
```

Arguments

- `name group_name`
  Specifies the name of the new probe group.

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

```
create_probe_group -name my_new_grp
```

delete_active_probe

Tcl command; deletes either all or the selected active probes.

**Note:** You cannot delete an individual probe from the Probe Bus.

```
delete_active_probe -all | -name probe_name
```

Arguments

- `all`
  Deletes all active probe names.
- `name probe_name`
  Deletes the selected probe names.

Supported Families

SmartFusion2, IGLOO2, and RTG4
Example

```bash
delete -all      # deletes all active probe names
delete -name out[5]:out[5]:Q \       # deletes the selected probe names
    -name my_grpl.out[1]:out[1]:Q
delete -name my_grpl \                # deletes the group, bus and their members.
    -name my_bus
```

ddr_read

Tcl command; reads the value of specified configuration registers pertaining to the DDR memory controller (MDDR/FDDR).

```bash
ddr_read -block ddr_name -name reg_name
```

Arguments

- `block <fddr || mddr || east_fddr || west_fddr>`
  - Specifies which DDR configurator is used in the Libero design.
  - SmartFusion2 and IGLOO2 - fddr and mddr
  - RTG4 - east_fddr and west_fddr
- `name register_name`
  - Specifies which configuration registers need to be read.

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

Read DDR Controller register DDRC_DYN_REFRESH_1_CR for a configured FDDR block on a SmartFusion2 or IGLOO2 device:

```bash
ddr_read -block fddr -name DDRC_DYN_REFRESH_1_CR
```

Returns

Returns 16-bit hexadecimal value.

The result of the command in the example above will be:

```
Register Name: DDRC_DYN_REFRESH_1_CR Value: 0x1234
“ddr_read” command succeeded.
```

ddr_write

Tcl command; writes the value of specified configuration registers pertaining to the DDR memory controller (MDDR/FDDR).

```bash
ddr_write -block ddr_name -name reg_name -value hex_value
```

Arguments

- `block <fddr || mddr || east_fddr || west_fddr>`
  - Specifies which DDR configurator is used in the Libero design.
  - SmartFusion2 and IGLOO2 - fddr and mddr
  - RTG4 - east_fddr and west_fddr
- **-name** `register_name`
  - Specifies which configuration registers need to be read.
  - A complete list of registers is available in the DDR Interfaces User Guides for the respective families.

- **-value** `hex_value`
  - Specifies the value to be written into the specified register of a given block.
  - Hex_value in the form of “0x12FA”.

### Supported Families

SmartFusion2, IGLOO2, and RTG4

### Example

Write a 16-bit value DDR Controller register DDRC_DYN_REFRESH_1_CR for a configured FDDR block on a SmartFusion2 or IGLOO2 device:

```
 ddr_write -block fddr -name DDRC_DYN_REFRESH_1_CR –value 0x123f
```

### Returns

Returns if the command succeeded or failed to execute.

"ddr_write" command succeeded

### event_counter

The event_counter Tcl command runs on signals that are assigned to channel A on the live probe, and displays the total events. It can be run before or after setting the live probe signal to channel A. The user specifies the duration to run the event_counter command.

```
 event_counter -run -stop –after duration_in_seconds
```

#### Arguments

- **-run**
  - Run event_counter.
- **-stop**
  - Stop event_counter.
- **-after** `duration_in_seconds`
  - Duration to stop event_counter. Specified by the user. This argument is required when -stop is specified.

### Supported Families

SmartFusion2, IGLOO2

### Example

```
set_live_probe -probeA {count_out_c[0]:Counter_8bit_0_count_out[0]:Q} -probeB {}

event_counter -run

event_counter -stop –after 10
```
Output

Device ID Code = 2F8071CF
The 'read_id_code' command succeeded.
Live probes have been assigned.
Channel A: count_out_c[0]:Counter_8bit_0_count_out[0]:Q
Channel B: Not specified

The 'set_live_probe' command succeeded.

Event Counter = Activated
The 'event_counter' command succeeded.

Event Counter = Stopped
Total Events = 1603561
The 'event_counter' command succeeded.

The Execute Script command succeeded.

export_smart_debug_data

Tcl command; exports debug data for the SmartDebug application.

```
export_smart_debug_data [device_components] [bitstream_components] [-file_name {file}] [-export_dir {dir}]
```

The command corresponds to the Export SmartDebug Data tool in Libero. The command creates a file with the extension "ddc" that contains data based on selected options. This file is used by SmartDebug to create a new SmartDebug project, or it can be imported into a device in SmartDebug.

- If you not specify any design components, all components available in the design will be included by default.
- The generate_bitstream parameter is required if you want to generate bitstream file and include it in the exported file.
- You must specify the bitstream components you want to include in the generated bitstream file or all available components will be included.
- If you choose to include bitstream, and the design has custom security, the custom security bitstream component must be included.

Arguments

**device_components**

The following device components can be selected. Specify "1" to include the component, and "0" if you do not want to include the component.

- `probes <1|0>`
- `package_pins <1|0>`
- `memory_blocks <1|0>`
- `envm_data <1|0>`
- `security_data <1|0>`
- `chain <1|0>`
- `programmer_settings <1|0>`
- `io_states <1|0>`

**bitstream_components**

The following bitstream components can be selected. Specify "1" to include the component, and "0" if you do not want to include the component.

- `generate_bitstream <1|0>`
- `bitstream_security <1|0>`
- `bitstream_fabric <1|0>`
-bitstream_envm <1|0>
-file_name file
Name of exported file with extension “ddc”.
-export_dir dir
Location where DDC file will be exported. If omitted, design export folder will be used.

**Supported Families**
SmartFusion2, IGLOO2, and RTG4

**Example**
The following example shows the export_smart_debug_data command with all parameters:
```
export_smart_debug_data \
-file_name {sd1} \
-export_dir {d:\sd_prj\test3T\designer\sd1\export} \
-probes 1 \n-package_pins 0 \n-memory_blocks 1 \n-envm_data 0 \n-security_data 1 \n-chain 1 \n-programmer_settings 1 \n-ios_states 1 \n-generate_bitstream 0 \n-bitstream_security 0 \n-bitstream_fabric 0 \n-bitstream_envm 0
```
The following example shows the command with no parameters:
```
export_smart_debug_data
```

**fhb_control**
This Tcl command provides FPGA Hardware Breakpoint (FHB) feature capability for SmartDebug.
```
fhb_control
 -halt -clock_domain clkDomName(s)/all
 -run -clock_domain clkDomName(s)
 -step number_of_steps -clock_domain clkDomName(s)
 -reset -clock_domain clkDomName(s)
 -arm_trigger -trigger_signal liveProbePoint -trigger_edge_select rising -delay value -
clock_domain clkDomName(s)
 -disarm_trigger -clock_domain clkDomName(s)/all
 -capture_waveform number_of_steps -vcd_file target_file_name
 -clock_domain_status -clock_domain clkDomName(s)/all
```

**Arguments**
- **-halt**
  Specifies to halt the clock.
  -clock_domain clkDomName(s)/all
  Specifies clock domain names to halt. Can be single or multiple clock domains, halted in order specified by user.
- **-run**
  Specifies to run the clock.
  -clock_domain clkDomName(s)
Specifies clock domain names to run. Can be single or multiple clock domains, releasing the user clock based on order specified.

-step number_of_steps

Specifies to step the clock "number_of_steps" times. Minimum value is 1.

-clock_domain clkDomName(s)

Specifies clock domain names to step. Can be single or multiple clock domains.

-reset

Specifies to reset FHB configuration for the specified clock domain.

-clock_domain clkDomName(s)

Specifies clock domain names to reset. Can be single or multiple clock domains.

-arm_trigger

Specifies to arm FHB configuration for the specified clock domain.

-trigger_signal liveProbePoint

Set the trigger signal to arm the FHBs.

-trigger_edge_select rising

Specifies the trigger signal edge to arm the FHBs. FHBs will be armed on rising edge of trigger signal.

-delay value

-clock_domain clkDomName(s)

Specifies clock domain names to be armed by the trigger signal. Can be single or multiple clock domains.

-disarm_trigger

Specifies to disarm FHB configuration for the specified clock domain.

-clock_domain clkDomName(s)

Specifies clock domain names to be reset by the trigger signal. Can be single or multiple clock domains.

-capture_waveform number_of_steps

Specifies to capture waveform of all the added signals to active probes in the specified clock domain for number_of_steps.

-vcd_file target_file_name

Target file to save the data and see the waveform.

-clock_domain_status clkDomName(s)/all

Specifies to read and display status of specified clock domain(s). Can be single or multiple clock domains.

**Supported Families**

SmartFusion2, IGLOO2

**Examples**

fhb_control -halt -clock_domain {"FCCC_0/GL0_INST" "FCCC_0/GL1_INST" }

fhb_control -run -clock_domain {"FCCC_0/GL0_INST" "FCCC_0/GL1_INST" }

fhb_control -step -clock_domain {"FCCC_0/GL0_INST" "FCCC_0/GL1_INST" }

fhb_control -reset -clock_domain {"FCCC_0/GL0_INST" "FCCC_0/GL1_INST" }

fhb_control -arm_trigger -trigger_signal {q_0_c[14]:count_1_q[14]:Q} -trigger_edge_select {rising} - delay 0 - clock_domain {"FCCC_0/GL0_INST" }

fhb_control -disarm_trigger -trigger_signal {q_0_c[14]:count_1_q[14]:Q} -trigger_edge_select {rising} - delay 0 - clock_domain {"FCCC_0/GL0_INST" }

fhb_control -capture_waveform {10} -vcd_file {D:/wvf_location/waveform.vcd}

fhb_control - clock_domain_status - clock_domain { "FCCC_0/GL0_INST" "FCCC_0/GL1_INST" "FCCC_0/GL2_INST" }

fhb_control - capture_waveform {10} -vcd_file {D:/wvf_location/waveform.vcd}
frequency_monitor

The frequency_monitor Tcl command calculates the frequency of a signal that is assigned to live probe A.

```
run_frequency_monitor -signal signal_name -time duration
```

**Arguments**

- `-signal signal_name`
  - Specifies the signal name.
- `-time duration`
  - Specifies the duration to run the command. The value can be 0.1, 1, 5, 8, or 10.

**Supported Families**

SmartFusion2, IGLOO2

**Example**

```
run_frequency_monitor -signal {count_out_c[7]:Counter_8bit_0_count_out[7]:Q} -time {5}
```

**Output**

```
Device ID Code = 2F8071CF
The 'read_id_code' command succeeded.

Frequency = 0.192716 MHz
The 'run_frequency_monitor' command succeeded.
The Execute Script command succeeded.
```

get_programmer_info

This Tcl command lists the IDs of all FlashPRO programmers connected to the machine.

```
get_programmer_info
```

This command takes no arguments.

**Supported Families**

SmartFusion2, IGLOO2, RTG4

**Example**

```
set a [get_programmer_info]
```

load_active_probe_list

Tcl command; loads the list of probes from the file.

```
load_active_probe_list -file file_path
```

**Arguments**

- `-file file_path`
  - The input file location.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4
Example

load_active_probe_list -file ".my_probes.txt"

**loopback_test**

Tcl command; used to start and stop the loopback tests.

<table>
<thead>
<tr>
<th>Command</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td><code>loopback_test [-deviceName device_name] -start -serdes num -lane num -type LoopbackType</code></td>
<td>Starts the loopback test.</td>
</tr>
<tr>
<td><code>loopback_test [-deviceName device_name] -stop -serdes num -lane num</code></td>
<td>Stops the loopback test.</td>
</tr>
</tbody>
</table>

**Arguments**

- **-deviceName device_name**
  Parameter is optional if only one device is available in the current configuration or set for debug (see the SmartDebug User's Guide for details).

- **-start**
  Starts the loopback test.

- **-stop**
  Stops the loopback test.

- **-serdes num**
  Serdes block number. Must be between 0 and 4 and varies between dies.

- **-lane num**
  Serdes lane number. Must be between 0 and 4

- **-type LoopbackType**
  Specifies the loopback test type. Must be **meso** (PCS Far End PMA RX to TX Loopback)

**Supported Families**

SmartFusion2, IGLOO2, RTG4

Example

```
loopback_test -start -serdes 1 -lane 1 -type meso
loopback_test -start -serdes 0 -lane 0 -type plesio
loopback_test -start -serdes 1 -lane 2 -type parallel
loopback_test -stop -serdes 1 -lane 2
```

**move_to_probe_group**

Tcl command; moves the specified probe points to the specified probe group.

*Note:* Probe points related to a bus cannot be moved to another group.

<table>
<thead>
<tr>
<th>Command</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td><code>move_to_probe_group -name probe_name -group group_name</code></td>
<td></td>
</tr>
</tbody>
</table>

**Arguments**

- **-name probe_name**
  Specifies one or more probes to move.

- **-group group_name**
  Specifies name of the probe group.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4
Example

```bash
move_to_probe_group -name out[5]:out[5]:Q 
   -name grp1.out[3]:out[3]:Q 
   -group my_grp2
```

prbs_test

Tcl command; used in PRBS test to start, stop, reset the error counter and read the error counter value.

```
prbs_test [-deviceName device_name] -start -serdes num -lane num [-near] -pattern PatternType
prbs_test [-deviceName device_name] -stop -serdes num -lane num
prbs_test [-deviceName device_name] -reset_counter -serdes num -lane num
prbs_test [-deviceName device_name] -read_counter -serdes num -lane num
```

Arguments

- **-deviceName device_name**
  Parameter is optional if only one device is available in the current configuration or set for debug (see the SmartDebug User's Guide for details).

- **-start**
  Starts the prbs test.

- **-stop**
  Stops the prbs test.

- **-reset_counter**
  Resets the prbs error count value to 0.

- **-read_counter**
  Reads and prints the error count value.

- **-serdes num**
  Serdes block number. Must be between 0 and 4 and varies between dies.

- **-lane num**
  Serdes lane number. Must be between 0 and 4.

- **-near**
  Corresponds to near-end (on-die) option for prbs test. Not specifying implies off-die.

- **-pattern PatternType**
  The pattern sequence to use for PRBS test. It can be one of the following: `prbs7`, `prbs11`, `prbs23`, or `prbs31`

Supported Families

SmartFusion2, IGLOO2, RTG4

Example

```
prbs_test -start -serdes 1 -lane 0 -near -pattern prbs11
prbs_test -start -serdes 2 -lane 2 -pattern custom -value all_zeros
prbs_test -start -serdes 0 -lane 1 -near -pattern user -value 0x0123456789ABCDEF0123
```
program_probe_insertion

This Tcl command runs the probe insertion flow on the selected nets.

Supported Families

SmartFusion2, IGLOO2, RTG4

read_active_probe

Tcl command; reads active probe values from the device. The target probe points are selected by the select_active_probe command.

read_active_probe [-deviceName device_name] [-name probe_name] [-group_name bus_name|group_name] [-value_type b|h][-file file_path]

Arguments

-deviceName device_name
Parameter is optional if only one device is available in the current configuration.

-name probe_name
Instead of all probes, read only the probes specified. The probe name should be prefixed with bus or group name if the probe is in the bus or group.

-group_name bus_name|group_name
Instead of all probes, reads only the specified buses or groups specified here.

-value_type b | h
Optional parameter, used when the read value is stored into a variable as a string.

b = binary

h = hex

-file file_path
Optional. If specified, redirects output with probe point values read from the device to the specified file.

Note: When the user tries to read at least one signal from the bus/group, the complete bus or group is read. The user is presented with the latest value for all the signals in the bus/group.

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

read_active_probe -group_name {bus1}
read_active_probe -group_name {group1}

To save into variable:

set a [read_active_probe -group_name {bus_name} -value_type h]   #save read data in hex string

If read values are stored into a variable without specifying value_type parameter, it saves values as a binary string by default.

Example

set a [read_active_probe ]   #sets variable a as binary string of read values after read_active_probe command.
read_analog_block_config
Reads each channel configuration on your analog system, enabling you to identify if/how each channel is configured.

```
read_analog_block_config [-name {device_name}] [-file {filename}]
```

**Arguments**

- `-name {device_name}`
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.

- `-file {filename}`
  (Optional) Identifies the name of the file to which read results will be saved.

**Supported Families**

Fusion

**Exceptions**

None

**Example**

The following command reads the analog block configuration information in the device ‘AFS600’:
```
read_analog_block_config -name AFS600
```

read_device_status
Displays the Device Information report; the Device Information report is a complete summary of your device state, analog block test values, user information, factory serial number and security information.

```
read_device_status [-name {device_name}] [-file {filename}]
```

**Arguments**

- `-name {device_name}`
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.

- `-file {filename}`
  (Optional) Identifies the name of the file to which read results will be saved.

**Supported Families**

SmartFusion, IGLOO, ProASIC3 and Fusion

**Exceptions**

None

**Example**

The following reads device info from the ‘AFS600’ device.
```
read_device_status -name AFS600
```
read_id_code

The command reads IDCode from the device without masking any IDCode fields. This is the raw IDcode from the silicon.

Note: Being able to read the IDCode is an indication that the JTAG interface is working correctly.

read_id_code [-name {device_name}]

Arguments

- **-name device_name**
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the set_debug_device command.

Supported Families

SmartFusion, IGLOO, ProASIC3 and Fusion

Exceptions

None

Example

The following command reads the IDCODE from the device 'AFS600':

```
read_id_code -name {AFS600}
```

read_flashrom

Reads the content of the FlashROM from the selected device.

read_flashrom [-name {device_name}] [-mapping {logical | physical}] [-file {filename}]

Arguments

- **-name device_name**
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the set_debug_device command.

- **-mapping {logical | physical}**
  (Optional) Specifies how the data read from the UFROM is mapped. Values are explained in the table below.

<table>
<thead>
<tr>
<th>Value</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>logical</td>
<td>Logical mapping (default)</td>
</tr>
<tr>
<td>physical</td>
<td>Physical mapping</td>
</tr>
</tbody>
</table>

- **-file {filename}**
  (Optional) Identifies the name of the file to which read results will be saved.

Supported Families

SmartFusion, IGLOO, ProASIC3 and Fusion
Exceptions

None

Example

The following reads the FROM content on the device ‘AFS600’ and sets to physical mapping:

```
read_flashrom -name {AFS600} -mapping {physical}
```

read_flash_memory

The command reads information from the NVM modules. There are two types of information that can be read:

- Page Status – includes ECC2 status, write count, access protection
- Page Data

```
read_flash_memory
[-name {device_name}]
[-block {integer_value}]
[-client {client_name}]
[-startpage {integer_value}]
[-endpage {integer_value}]
[-access {all | status | data}]
[-file {filename}]
```

At a minimum you must specify `-client <name>` OR

```
-st startpage <page_number> -en endpage <page_number> -bl block <number>
```

Arguments

- `-name {device_name}`
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.

- `-block {integer_value}`
  (Optional argument; you must set -client or –startpage and –endpage before use.) Specifies location of block for memory read.

- `-client {client_name}`
  Name of client for memory read.

- `-startpage {integer_value}`
  Startpage for page range; value must be an integer. You must specify a –endpage and -block along with this argument.

- `-endpage {integer_value}`
  Endpage for page range; value must be an integer. You must specify a –startpage and -block along with this argument.

- `-access {all | status | data}`
  (Optional argument; you must set -client or –startpage, –endpage and –block before use.) Specifies what eNVM information to check: page status, data or both.

<table>
<thead>
<tr>
<th>Value</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>all</td>
<td>Shows the number of pages with corruption status, data corruption and out-of-range write count (default)</td>
</tr>
<tr>
<td>status</td>
<td>Shows the number of pages with corruption status and the number of pages with out-of-range write count</td>
</tr>
<tr>
<td>Value</td>
<td>Description</td>
</tr>
<tr>
<td>-------</td>
<td>-------------</td>
</tr>
<tr>
<td>data</td>
<td>Shows only the number of pages with data corruption</td>
</tr>
</tbody>
</table>

`-file {filename}`

(Optional argument; you must set -client or –startpage, –endpage and –block before use.) Name of output file for memory read.

**Supported Families**

SmartFusion, Fusion

**Exceptions**

None

**Example**

The following command reads the flash memory for the client 'DS8bit' and reports the data in a logfile 'readFlashMemoryReport.log':

```shell
read_flash_memory -client {DS8bit} -file {readFlashMemoryReport.log}
read_flash_memory –startpage 0 –endpage 2 –block 0 –access {data}
```

**read_lsram**

Tcl command; reads a specified block of large SRAM from the device.

**Physical block**

```bash
read_lsram [-deviceName device_name] -name block_name [-fileName file_name]
```

**Arguments**

- `-deviceName device_name`
  - Parameter is optional if only one device is available in the current configuration or set for debug (see SmartDebug help for details).
- `-name block_name`
  - Specifies the name for the target block.
- `-fileName file_name`
  - Optional; specifies the output file name for the data read from the device.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4

**Exceptions**

- Array must be programmed and active
- Security locks may disable this function

**Example**

Reads the SRAM Block sram_block1 from the sf2 device and writes it to the file sram_block_output.

```bash
read_lsram [-deviceName sf2] -name sram_block1 [-file sram_block_output]
```
Logical block

`read_lsram -logicalBlockName block_name -port port_name [-fileName filename]`

**Arguments**

- `-logicalBlockName block_name`
  Specifies the name for the user defined memory block.
- `-port port_name`
  Specifies the port for the memory block selected. Can be either Port A or Port B.
- `-file filename`
  Optional; specifies the output file name for the data read from the device.

**Example**

`read_lsram -logicalBlockName {Fabric_Logic_0/U2/F_0_F0_U1} -port {Port A}`

read_usram

Tcl command; reads a uSRAM block from the device.

Physical block

`read_usram [-deviceName device_name] -name block_name [-fileName file_name]`

**Arguments**

- `-deviceName device_name`
  Parameter is optional if only one device is available in the current configuration or set for debug (see SmartDebug help for details).
- `-name block_name`
  Specifies the name for the target block.
- `-fileName file_name`
  Optional; specifies the output file name for the data read from the device.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4

**Exceptions**

- Array must be programmed and active
- Security locks may disable this function

**Example**

Reads the uSRAM Block usram_block2 from the sf2 device and writes it to the file sram_block_output.

`read_usram [-deviceName sf2] -name usram_block2 [-fileName sram_block_output]`

Logical block

`read_usram -logicalBlockName block_name -port port_name [-fileName filename]`

**Arguments**

- `-logicalBlockName block_name`
  Specifies the name for the user defined memory block.
- `-port port_name`
Specifies the port for the memory block selected. Can be either Port A or Port B.

- **file** `filename`
  
  Optional; specifies the output file name for the data read from the device.

**Example**

read_usram -logicalBlockName {Fabric_Logic_0/U3/F_0_F0_U1} -port {Port A}

---

### recover_flash_memory

The command removes ECC2 errors due to memory corruption by reprogramming specified flash memory (NVM) pages and initializing all pages to zeros. The recovery affects data blocks and auxiliary blocks.

The write counters of the corrupted pages might not be accurate due to corruption. The recovery operation will not change state of the page write counters.

Use the `check_flash_memory` command to detect flash memory errors.

```
recover_flash_memory
[-name {device_name}]
[-block {integer_value}]
[-client {client_name}]
[-startpage {integer_value}]
[-endpage {integer_value}]
```

At a minimum you must specify `-client <name>` OR `-startpage <page_number> -endpage <page_number> -block <number>`

**Arguments**

- **-name** `{device_name}`
  
  Optional user-defined device name. The device name is not required if there is only one device in the current configuration, or a device has already been selected using the `set_debug_device` command.

- **-block** `{integer_value}`
  
  (Optional argument; you must set `-client` or `-startpage` and `-endpage` before use.) Specifies location of block for memory recovery.

- **-client** `{client_name}`
  
  Name of client for memory recovery.

- **-startpage** `{integer_value}`
  
  Startpage for page range; value must be an integer. You must specify a `-endpage` and `-block` along with this argument.

- **-endpage** `{integer_value}`
  
  Endpage for page range; value must be an integer. You must specify a `-startpage` and `-block` along with this argument.

**Supported Families**

SmartFusion, Fusion

**Exceptions**

None

**Example**

The following command recovers flash memory data in the client 'DS8bit':

```
recover_flash_memory -client {DS8bit}
```

The following command recovers flash memory from block 0, startpage 0, and endpage 3:

```
recover_flash_memory -block 0 -startpage 0 -endpage 3
```
remove_from_probe_group

Tcl command; removes the specified probe points from the group. That is, the removed probe points won’t be associated with any probe group.

**Note:** Probes cannot be removed from the bus.

```bash
remove_from_probe_group -name probe_name
```

**Arguments**

- `-name probe_name`

  Specifies one or more probe points to remove from the probe group.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4

**Example**

The following command removes two probes from my_grp2.

```bash
move_out_of_probe_group -name my_grp2.out[3]:out[3]:Q \
  -name my_grp2.out[3]:out[3]:Q
```

remove_probe_insertion_point

This Tcl command deletes an added probe from the probe insertion UI.

```bash
remove_probe_insertion_point -net net_name -driver driver
```

**Arguments**

- `-net net_name`

  Name of the existing net which is added using the `add_probe_insertion_point` command.

- `-driver driver`

  Driver of the net.

**Supported Families**

SmartFusion2, IGLOO2, RTG4

**Example**

```bash
remove_probe_insertion_point -net {count_out_c[0]} -driver 
  {Counter_8bit_0_count_out[0]:Q}
```

sample_analog_channel

Performs analog-to-digital conversion of a selected analog channel. This command is used when debugging the Analog Subsystem and is performed on the pre-configured analog channel with user-supplied ADC conversion parameters. The command also performs digital filtering using a single-pole low-pass filter if you opt to use it.

```bash
sample_analog_channel [--name {name}] * 
[-resolution {8 | 10 | 12}] 
[-clock_periods {int_value}] 
[-clock_divider {int_value}] 
[-num_samples {int_value}] 
[-filtering_factor {real_value}]
```
Arguments

$name$ (name)

Specifies the analog channel to be sampled. Channel name is a combination of the channel type followed by the channel index. Valid channel names are listed in the table below.

<table>
<thead>
<tr>
<th>Family</th>
<th>Valid Channel Name</th>
</tr>
</thead>
<tbody>
<tr>
<td>Fusion</td>
<td>AV&lt;n&gt;, AT&lt;n&gt;, AC&lt;n&gt;</td>
</tr>
<tr>
<td>SmartFusion</td>
<td>AV&lt;n&gt;, AT&lt;n&gt;, AC&lt;n&gt;, ADC&lt;n&gt;</td>
</tr>
</tbody>
</table>

The maximum number of channels depends on particular device type; refer to the Analog Block specification in the device handbook.

$resolution$ (8 | 10 | 12)

ADC conversion resolution. Specifies bit size of the conversion results. Selection of certain resolutions may affect timing parameter valid ranges. See your device handbook for details.

$clock_periods$ (int_value)

Parameter specifying sampling time: Sampling_time = clock_periods * adc_clock_period.

$clock_divider$ (int_value)

Specifies clock prescaling factor.

$num_samples$ (int_value)

Optional argument that specifies the number of samples to be performed by the ADC. Default number of samples is 1. Selecting multiple vs single sample will change appearance of the generated report. For the single sample a single result is shown and if "show_details" is set to "yes" then detailed status of the ADC register is also shown.

If multiple samples are requested then the results are printed in a table. If the digital filtering is enabled the table also includes filtered results.

$filtering_factor$ (real_value)

Optional argument that specifies the filtering factor if multiple samples requested. The default value of 1.0 disables digital filtering.

$initial_value$ (int_value)

Optional argument that specifies the initial value for the digital averaging filter. The value is specified in ADC register counts. Default value is set to 0. Specifying this parameter improves filtering process during initial samples.

$show_details$ (yes | no)

Optional argument that specifies the level of the report output. Detailed output includes initial user-supplied conversion parameters. For the single-sampling case final output also includes detailed content of ADC register after sampling.

$filename$

Optional argument. Specifies name of output file for conversion results.

Supported Families

SmartFusion and Fusion

Exceptions

None
Example

The following example performs single sample analog-to-digital conversion for channel AV0:

```
sample_analog_channel -channel AV0 -resolution 8 -clock_periods 4 -clock_divider 4
```

Example with multiple sampling and digital signal filtering for AV0:

```
sample_analog_channel -channel AV0 -resolution 10 -clock_periods 4 -clock_divider 4 -num_samples 10 -filtering_factor 2.5
```

save_active_probe_list

Tcl command; saves the list of active probes to a file.

```
save_active_probe_list -file file_path
```

Arguments

- **-file file_path**
  The output file location.

 Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

```
save_active_probe_list -file ".my_probes.txt"
```

select_active_probe

Tcl command; manages the current selection of active probe points to be used by active probe READ operations. This command extends or replaces your current selection with the probe points found using the search pattern.

```
select_active_probe [-deviceName device_name] [-name probe_name_pattern] [-reset true|false]
```

Arguments

- **-deviceName device_name**
  Parameter is optional if only one device is available in the current configuration.

- **-name probe_name_pattern**
  Specifies the name of the probe. Optionally, search pattern string can specify one or multiple probe points. The pattern search characters "*" and "?" also can be specified to filter out the probe names.

- **-reset true | false**
  Optional parameter; resets all previously selected probe points. If name is not specified, empties out current selection.

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

The following command selects three probes. In the below example, “grp1” is a group and “out” is a bus.

```
Select_active_probe -name out[5]:out[5]:Q
Select_active_probe -name out.out[1]:out[1]:Q \
  -name out.out[3]:out[3]:Q \
  -name out.out[5]:out[5]:Q
```
serdes_lane_reset

Tcl command. In EPCS mode, this command resets the lane. In PCI mode, this command resets the lane, all other lanes in the link, and the corresponding PCIe controller. The result is shown in the log window/console.

serdes_lane_reset -serdes num -lane num

Arguments

- **-serdes num**
  The SERDES block number. It must be between 0 and varies between dies. It must be one of the SERDES blocks used in the design.

- **-lane num**
  The SERDES lane number. It must be between 0 and 3. It must be one of the lanes enabled for the block in the design.

Supported Families

- SmartFusion2, IGLOO2, and RTG4

Example

serdes_lane_reset -serdes 0 -lane 0
In EPCS mode, resets Lane 0, for block 0. In PCI mode, resets Lane 0 for block 0, all other lanes in the same link for block 0

serdes_lane_reset -serdes 5 -lane 3

Errors

The following errors result in the failure of the Tcl command and the corresponding message on the smart debug log window:

- **When the “-serdes” parameter is not specified:**
  Error: Required parameter 'serdes' is missing.
  Error: Failure when executing Tcl script. [Line 26: Error in command serdes_lane_reset]
  Error: The Execute Script command failed.

- **When the “-lane” parameter is not specified:**
  Error: Required parameter 'lane' is missing.
  Error: Failure when executing Tcl script. [Line 26: Error in command serdes_lane_reset]
  Error: The Execute Script command failed.

- **When "block number" is not specified:**
  Error: Parameter 'serdes' has illegal value.
  Error: Failure when executing Tcl script. [Line 26: Error in command serdes_lane_reset]
  Error: The Execute Script command failed.

- **When "lane number" is not specified:**
  Error: Required parameter 'lane' is missing.
  Error: Failure when executing Tcl script. [Line 26: Error in command serdes_lane_reset]
  Error: The Execute Script command failed.

- **When "block number" is invalid:**
  Error: Phy Reset: Serdes block number should be one of the following: 0
  Error: The command 'serdes_lane_reset' failed.
  Error: Failure when executing Tcl script. [Line 26]
  Error: The Execute Script command failed.

Note: Only the SERDES blocks used the design will be mentioned in the above list.
When “lane number” is invalid:
  Error: Phy Reset: Serdes lane number should be between 0 and 3.
  Error: The command 'serdes_lane_reset' failed.
  Error: Failure when executing Tcl script. [Line 26]
  Error: The Execute Script command failed.

For all the above scenarios, the following message appears:

![Error message]

serdes_read_register

Tcl command; reads the SERDES register value and displays the result in the log window/console.

```
serdes_read_register -serdes num [ -lane num ] -name REGISTER_NAME
```

Arguments

- **-serdes num**
  SERDES block number. Must be between 0 and and varies between dies.
- **-lane num**
  SERDES lane number. Must be between 0 and 3.

The lane number must be specified when the lane register is used. Otherwise, the command will fail.

When the lane number is specified along with the SYSTEM or PCIe register, the command will fail with an error message, as the lane is not applicable to them.

- **-name REGISTER_NAME**
  Name of the SERDES register.

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

```
serdes_read_register -serdes 0 -name SYSTEM_SER_PLL_CONFIG_HIGH
serdes_read_register -serdes 0 -lane 0 -name CR0
```

serdes_write_register

```
serdes_write_register
```

UG0567: RTG4 High-Speed Serial Interfaces User Guide (includes all SERDES register names)

UG0447: SmartFusion2 and IGLOO2 FPGA High-Speed Serial Interfaces User Guide

serdes_write_register

Tcl command; writes the value to the SERDES register. Displays the result in the log window/console.

```
serdes_write_register -serdes num [ -lane num ] -name REGISTER_NAME -value 0x1234
```
Arguments
- `serdes num`
  SERDES block number. Must be between 0 and 5 and varies between dies.
- `lane num`
  SERDES lane number. Must be between 0 and 3.
  The lane number should be specified when the lane register is used. Otherwise, the command will fail.
  When the lane number is specified along with the SYSTEM or PCIe register, the command will fail with an
  error message, as the lane is not applicable to them.
- `name REGISTER_NAME`
  Name of the SERDES register.
- `value`
  Specify the value in hexadecimal format.

Supported Families
SmartFusion2, IGLOO2, and RTG4

Example
```
serdes_write_register -serdes 0 -name SYSTEM_SER_PLL_CONFIG_HIGH -value 0x5533
```

See Also
serdes_read_register.htm
UG0567: RTG4 High-Speed Serial Interfaces User Guide (includes all SERDES register names)
UG0447: SmartFusion2 and IGLOO2 FPGA High-Speed Serial Interfaces User Guide

set_debug_device
Identifies the device you intend to debug.
```
set_debug_device -name {device_name}
```

Arguments
- `name {device_name}`
  Device name. The device name is not required if there is only one device in the current configuration.

Supported Families
SmartFusion, IGLOO, ProASIC3 and Fusion

Exceptions
None

Example
The following example identifies the device ‘A3P250’ for debugging:
```
set_debug_device -name {A3P250}
```

set_debug_programmer
Identifies the programmer you want to use for debugging (if you have more than one). The name of the
programmer is the serial number on the bar code label on the FlashPro programmer.
set_debug_programmer -name {programmer_name}

Arguments
- name {programmer_name}

Programmer name is the serial number on the bar code label of the FlashPro programmer.

Supported Families
SmartFusion, IGLOO, ProASIC3 and Fusion

Exceptions
None

Example
The following example selects the programmer 10841
set_debug_programmer -name {10841}

set_live_probe
Tcl command; set_live_probe channels A and/or B to the specified probe point(s). At least one probe point must be specified. Only exact probe name is allowed (i.e. no search pattern that may return multiple points).

set_live_probe [-deviceName device_name] [-probeA probe_name] [-probeB probe_name]

Arguments
- deviceName device_name
  Parameter is optional if only one device is available in the current configuration or set for debug (see SmartDebug user guide for details).
- probeA probe_name
  Specifies target probe point for the probe channel A.
- probeB probe_name
  Specifies target probe point for the probe channel B.

Supported Families
SmartFusion2, IGLOO2, RTG4

Exceptions
- The array must be programmed and active
- Active probe read or write operation will affect current settings of Live probe since they use same probe circuitry inside the device
- Setting only one Live probe channel affects the other one, so if both channels need to be set, they must be set from the same call to set_live_probe
- Security locks may disable this function
- In order to be available for Live probe, ProbeA and ProbeB I/O's must be reserved for Live probe respectively

Example
Sets the Live probe channel A to the probe point A12 on device sf2.
set_live_probe [-deviceName sf2] [-probeA A12]
ungroup

Tcl command; disassociates the probes as a group.

```
ngroup -name group_name
```

**Arguments**

- `-name group_name`
  
  Name of the group.

**Supported Families**

SmartFusion2, IGLOO2, and RTG4

**Example**

```
ungroup -name my_grp4
```

unset_live_probe

Tcl command; discontinues the debug function and clears both live probe channels (Channel A and Channel B). An all zeros value is shown for both channels in the oscilloscope.

*Note:* For RTG4, only one probe channel (Probe Read Data Pin) is available.

```
unset_live_probe [-deviceName device_name]
```

**Arguments**

- `-deviceName device_name`
  
  Parameter is optional if only one device is available in the current configuration or set for debug (see the SmartDebug User’s Guide for details).

**Supported Families**

SmartFusion2, IGLOO2, and RTG4

**Exceptions**

- The array must be programmed and active.
- Active probe read or write operation affects current of Live Probe settings, because they use the same probe circuitry inside the device.
- Security locks may disable this function.

**Example**

The following example unsets both live probe channels (Channel A and Channel B) from the device sf2.

```
unset_live_probes [-deviceName sf2]
```

write_active_probe

Tcl command; sets the target probe point on the device to the specified value. The target probe point name must be specified.

```
write_active_probe [-deviceName device_name] -name probe_name -value true|false
-group_name group_bus_name -group_value "hex-value" | "binary-value"
```
Arguments

- **deviceName** *device_name*
  Parameter is optional if only one device is available in the current configuration.

- **name** *probe_name*
  Specifies the name for the target probe point. Cannot be a search pattern.

- **value** *true | false hex-value | binary-value*
  Specifies values to be written.
  True = High
  False = Low

- **group_name** *group_bus_name*
  Specify the group or bus name to write to complete group or bus.

- **group_value** "hex-value" | "binary-value"
  Specify the value for the complete group or bus.
  Hex-value format: "<size>'h<value>"
  Binary-value format: "<size>'b<value>"

Supported Families

SmartFusion2, IGLOO2, and RTG4

Example

```
write_active_probe -name out[5]:out[5]:Q -value true <-- write to a single probe
write_active_probe -name grp1.out[3]:out[3]:Q -value low <-- write to a probe in the group
write_active_probe -group_name grp1 -group_value "8'hF0" <-- write the value to complete group
write_active_probe -group_name out -group_value "8'b11110000" \\
  -name out[2]:out[2]:Q -value true <-- write multiple probes at the same time.
```

**write_lsram**

Tcl command; writes a seven bit word into the specified large SRAM location.

Physical block

```
write_lsram [-deviceName *device_name*] -name *block_name* -offset *offset_value* -value *value*
```

Arguments

- **deviceName** *device_name*
  Parameter is optional if only one device is available in the current configuration or set for debug (see SmartDebug help for details).

- **name** *block_name*
  Specifies the name for the target block.

- **offset** *offset_value*
  Offset (address) of the target word within the memory block.

- **value** *value*
  Nine-bit value to be written to the target location.

Supported Families

SmartFusion2, IGLOO2, and RTG4
Exceptions

- Array must be programmed and active
- The maximum value that can be written is 0x1FF
- Security locks may disable this function

Example

Writes a value of 0x1A to the device sf2 in the block sram_block1 with an offset of 16.

```bash
write_lsrarn [-deviceName sf2] -name sram_block1 -offset 16 -value 0x1A
```

Logical block

```bash
write_lsrarn -logicalBlockName block_name -port port_name -offset offset_value -logicalValue hexadecimal_value
```

Arguments

- **-logicalBlockName block_name**
  
  Specifies the name for the user defined memory block.

- **-port port_name**
  
  Specifies the port for the memory block selected. Can be either Port A or Port B.

- **-offset offset_value**
  
  Offset (address) of the target word within the memory block.

- **-logicalValue hexadecimal_value**
  
  Specifies the hexadecimal value to be written to the memory block. Size of the value is equal to the width of the output port selected.

Example

```bash
write_lsrarn -logicalBlockName {Fabric_Logic_0/U2/F_0_F0_U1} -port {Port A} -offset 1 -logicalValue {00FFF}
```

write_usram

Tcl command; writes a seven bit word into the specified uSRAM location.

Physical block

```bash
write_usram [-deviceName device_name] -name block_name] -offset offset_value -value value
```

Arguments

- **-deviceName device_name**
  
  Parameter is optional if only one device is available in the current configuration or set for debug (see SmartDebug help for details).

- **-name block_name**
  
  Specifies the name for the target block.

- **-offset offset_value**
  
  Offset (address) of the target word within the memory block.

- **-value value**
  
  Nine-bit value to be written.
**Supported Families**
SmartFusion2, IGLOO2, and RTG4

**Exceptions**
- Array must be programmed and active
- The maximum value that can be written is 0x1FF
- Security locks may disable this function

**Example**
Writes a value of 0x1A to the device sf2 in the block usram_block2 with an offset of 16.

```
write_usram [-deviceName sf2] -name usram_block2 -offset 16 -value 0x1A
```

**Logical block**
```
write_usram -logicalBlockName block_name -port port_name -offset offset_value -logicalValue hexadecimal_value
```

**Arguments**
- **-logicalBlockName block_name**
  Specifies the name for the user defined memory block.
- **-port port_name**
  Specifies the port for the memory block selected. Can be either Port A or Port B.
- **-offset offset_value**
  Offset (address) of the target word within the memory block.
- **-logicalValue hexadecimal_value**
  Specifies the hexadecimal value to be written to the memory block. Size of the value is equal to the width of the output port selected.

**Example**
```
write_usram -logicalBlockName {Fabric_Logic_0/U3/F_0_F0_U1} -port {Port A} -offset 1 -logicalValue {00FFF}
```
Solutions to Common Issues Using SmartDebug

Embedded Flash Memory (NVM) - Failure when Programming/Verifying

If the Embedded Flash Memory failed verification when executing the PROGRAM_NVM, VERIFY_NVM or PROGRAM_NVM_ACTIVE_ARRAY action, the failing page may be corrupted. To confirm and address this issue:

1. In the Inspect Device window click View Flash Memory Content.
2. Select the Flash Memory block and client (or page range) to retrieve from the device.
3. Click Read from Device; the retrieved data appears in the lower part of the window.
4. Click View Detailed Status to check the NVM Status.

   Note: You can use the check_flash_memory and read_flash_memory Tcl commands to perform diagnostics similar to the commands outlined above.

5. If the NVM is corrupted you must reset the affected NVM pages.
   To reset the corrupted NVM pages, either re-program the pages with your original data or ‘zero-out’ the pages by using the Tcl command recover_flash_memory.

If the Embedded Flash Memory failed verification when executing a VERIFY_NVM or VERIFY_NVM_ACTIVE_ARRAY action, the failure may be due to the change of content in your design. To confirm this, repeat steps 1-3 above.

   Note: NVM corruption is still possible when writing from user design. Check NVM status for confirmation.

Analog System Not Working as Expected

If the Analog System is not working correctly, it may be due the following:

1. System supply issue. To troubleshoot:
   - Physically verify that all the supplies are properly connected to the device and they are at the proper level. Then confirm by running the Device Status.
   - Physically verify that the relevant channels are correctly connected to the device.
2. Analog system is not properly configured. You can confirm this by examining the Analog System.

ADC Not Sampling the Correct Value

If the ADC is sampling all zero values then the wrong analog pin may be connected to the system, or the analog pin is disconnected. If that is not the case and the ADC is not sampling the correct value, it may be due to the following:

1. System supply issues - Run the device status to confirm.
2. Analog system is not configured at all - To confirm, read out the ACM configuration and verify if the ACM content is all zero.
3. Analog system is not configured correctly - To confirm, read out the ACM configuration and verify that the configuration is as expected.

   Once analog block configuration has been confirmed, you can use the sample_analog_channel Tcl command for debug sampling of the analog channel with user-supplied sampling parameters.

   If you have access to your Analog System Builder settings project (<Libero IDE project>/Smartgen/AnalogBlock), you may use the compare function provided by the tool.
Frequently Asked Questions

How do I unlock the device security so I can debug?
You must provide the PDB file with a User Pass Key in order to unlock the device and continue debugging. If you do not have a PDB with User Pass Key, you can create a PDB file in FlashPro (if you know the Pass Key value).

How do I export a report?
You can export three reports from the SmartDebug GUI: Device Status, Client Detailed Status from the NVM, or the Compare Client Content report from the NVM. Each of those reports can be saved and printed.
If using a Tcl command, you can use the -file <filename> option for the following commands:

read flash memory
check flash memory
compare memory client
read device status
read flashrom
read analog block config
sample analog channel
compare flashrom client
compare analog config

For example, you can use the following command to export the content of the client ‘datastore1’ in NVM block 0 to the report file datastore1_content.txt:
read flash_memory -client "datastore1" -file {C:\temp\datastore1_content.txt}
For more information about Tcl commands supported by SmartDebug, see SmartDebug Tcl Commands.

How do I generate diagnostic reports for my target device?
A set of diagnostic reports can be generated for your target device depending on which silicon feature you are debugging. A set of Tcl commands are available to export those reports. The following is a summary of those Tcl commands based on the silicon features.

When using the –file parameter, ensure that you use a different file name for each command so you do not overwrite the report content. If you do not specify the –file option in the Tcl, the output results will be directed to the FlashPro log window.

For the overall device:
read device status
read id code

For FlashROM:
compare flashrom client
read flashrom

For Embedded Flash Memory (NVM):
compare memory client
check flash memory
read flash memory

For Analog Block:
read analog block config
compare analog config
To execute the Tcl command, from the File menu choose Run Script.

How do I monitor a static or pseudo-static signal?

To monitor a static or pseudo-static signal:
1. Add the signal to the Active Probes tab.
2. Select the signal in the Active Probes tab, right-click, and choose Poll....
3. In the Pseudo-static Signal Polling dialog box, choose a value in Polling Setup and click Start Polling.

How do I force a signal to a new value?

To force a signal to a new value:
1. In the SmartDebug window, click Debug FPGA Array.
2. Click the Active Probes tab.
3. Select the signal from the selection panel and add it to Active Probes tab.
1. Click **Read Active Probe** to read the value.
2. In the Write Value column, enter the value to write to the signal and then click **Write Active Probes**.

How do I count the transitions on a signal?

If FHB IP is auto-instantiated in the design, you can use the Event Counter in the **Live Probes** tab to count the transitions on a signal.

To count the transitions on a signal:

1. Assign the desired signal to Live Probe Channel A.
2. Click the **Event Counter** tab and check the Activate Event Counter checkbox.
How do I monitor or measure a clock?

You can monitor a clock signal from the Live Probe tab when the design is synthesized and compiled with FHB Auto Instantiation turned on in Project Settings dialog box (Enhanced Constraint Flow).

In the Live Probe tab, SmartDebug allows you to:

1. Measure all the FABCCC GL clocks by clicking the User Clock Frequencies tab, as shown in the figure below.
2. Monitor frequencies of any probe points by:
   a. Assigning the desired signal to Live Probe Channel A.
   b. Selecting the Frequency Monitor tab as shown in the following figure and checking the Activate Frequency Meter checkbox.
How do I perform simple PRBS and loopback tests?

You can perform PRBS and loopback tests using the Debug SERDES option in SmartDebug.

To perform a PRBS test, in the Debug SERDES dialog box, select **PRBS Test** to run a PRBS test on-die or off-die. For more information, see "Debug SERDES — PRBS Test" on page Error! Bookmark not defined.

To perform a loopback test, in the Debug SERDES dialog box, select **Loopback Test** to run a near end serial loopback /far end PMA Rx to Tx loopback test. For more information, see "Debug SERDES — Loopback Test" on page Error! Bookmark not defined.

How do I read LSRAM or USRAM content?

To read RAM content:

1. In the Debug FPGA Array dialog box, click the **Memory Blocks** tab.
2. Select the memory block to be read from the selection panel on the left of the window.
An "L" in the icon next to the block name indicates that it is a logical block, and a "P" in the icon indicates that it is a physical block. A logical block displays three fields in the Memory Blocks tab: User Design Memory Blocks, Data Width, and Port Used. A physical block displays two fields in the Memory Blocks tab: User Design Memory Block and Data Width.

3. Add the block in one of the following ways:
   a. Click **Select**.
   b. Right-click and choose **Add**.
   c. Drag the block to the **Memory Blocks** tab.

4. Click **Read Block** to read the content of the block.

**See Also**

"Memory Blocks (SmartFusion2, IGLOO2, RTG4)" on page Error! Bookmark not defined."Memory Blocks (SmartFusion2, IGLOO2, RTG4)" on page Error! Bookmark not defined.
How do I change the content of LSRAM or USRAM?

To change the content of LSRAM or USRAM:
1. In the SmartDebug window, click **Debug FPGA Array**.
2. Click the **Memory Blocks** tab.
3. Select the memory block from the selection panel on the left of the window.

An "L" in the icon next to the block name indicates that it is a logical block, and a "P" in the icon indicates that it is a physical block. A logical block displays three fields in the Memory Blocks tab: User Design Memory Blocks, Data Width, and Port Used. A physical block displays two fields in the Memory Blocks tab: User Design Memory Block and Data Width.

4. Add the memory block in one of the following ways:
   a. Click **Select**.
   b. Right-click and choose **Add**.
   c. Drag the block to the **Memory Blocks** tab.
5. Click **Read Block**. The memory content matrix is displayed.
6. Select the memory cell value that you want to change and update the value.
7. Click **Write Block** to write to the device.
See Also
"Memory Blocks (SmartFusion2, IGLOO2, RTG4)" on page Error! Bookmark not defined.
"Memory Blocks (SmartFusion2, IGLOO2, RTG4)" on page Error! Bookmark not defined.

How do I read the health check of the SERDES?

You can read the SERDES health check using the following Debug SERDES options:

1. Review the **Configuration Report**, which returns PMA Ready, TxPLL status, and RxPLL status. For SERDES to function correctly, PMA ready should be true, and TxPLL and RxPLL status should be locked. The Configuration Report can be found in the Debug SERDES dialog box under Configuration. See Debug SERDES (SmartFusion2, IGLOO2, and RTG4).

2. Run the **PRBS Test**, which is a Near End Serial Loopback tests on selected lanes. This should result in 0 errors in the Cumulative Error Count column. See "Debug SERDES – PRBS Test" on page Error! Bookmark not defined..

Where can I find files to compare my contents/settings?

**FlashROM**

You can compare the FlashROM content in the device with the data in the PDB file. You can find the PDB in the `<Libero IDE project>/Designer/Impl` directory.

**Embedded Flash Memory (NVM)**

You can compare the Embedded Flash Memory content in the device with the data in the PDB file. You can find the PDB in the `<Libero IDE project>/Designer/Impl` directory.

**Analog System**

You can compare the Analog System configuration in the device with the data in the loaded PDB file or in the Analog System folder. Go to:

- Fusion devices - `<Libero IDE project>/Smartgen/AnalogBlock`
- SmartFusion devices - `<Libero IDE Project>/component/<SmartDesign Project>/MSS_ACE_0`

The tool automatically identifies the necessary files in the selected folder for comparison.
What is a UFC file? What is an EFC file?

UFC is the User FlashROM Configuration file, generated by the FlashROM configurator; it contains the partition information set by the user. It also contains the user-selected data for region types with static data. However, for AUTO_INC and READ_FROM_FILE, regions the UFC file contains only:

- Start value, end value, and step size for AUTO_INC regions, and
- File directory for READ_FROM_FILE regions

EFC is the Embedded Flash Configuration file, generated by the Flash Memory Builder in the Project Manager Catalog; it contains the partition information and data set by the user. Both UFC and EFC information is embedded in the PDB when you generate the PDB file.

Is my FPGA fabric enabled?

When your FPGA fabric is programmed, you will see the following statement under Device State in the Device Status report:

FPGA Array Status: Programmed and Enabled

If the FPGA fabric is not programmed, the Device State shows:

FPGA Array Status: Not Enabled
Embedded Flash Memory (NVM) Frequently Asked Questions

Is my Embedded Flash Memory (NVM) programmed?
To figure out if your NVM is programmed, read out and view the NVM content or perform verification with the PDB file. To examine the NVM content, see the FlashROM Memory Content Dialog Box. To verify the NVM with the PDB select the VERIFY or VERIFY_NVM action in FlashPro.

How do I display Embedded Flash Memory (NVM) content in the Client partition?
You must load your PDB into your FlashPro project in order to view the Embedded Flash Memory content in the Client partition. To view NVM content in the client partition:
1. Load your PDB into your FlashPro project.
2. Click Inspect Device.
3. Click View Flash Memory Content.
4. Choose a block from the drop-down menu.
5. Select a client.
6. Click Read from Device. The Embedded Flash Memory content from the device appears in the Flash Memory dialog box.
See the Flash Memory Dialog Box topic for more description on viewing the NVM content.

How do I know if I have Embedded Flash Memory (NVM) corruption?
When Embedded Flash Memory is corrupted, checking Embedded Flash Memory may return with any or all of the following page status:
- ECC1/ECC2 failure
- Page write count exceeds the 10-year retention threshold
- Page write count is invalid
- Page protection is set illegally (set when it should not be)
See the How do I interpret data in the Flash Memory (NVM) Status Report? topic for details. If your Embedded Flash Memory is corrupted, you can recover by reprogramming with original design data. Alternatively, you can ‘zero-out’ the pages by using the Tcl command recover_flash_memory.

Why does Embedded Flash Memory (NVM) corruption happen?
Embedded Flash Memory corruption occurs when Embedded Flash Memory programming is interrupted due to:
- Supply brownout; monitor power supplies for brownout conditions. For SmartFusion monitor the VCC_ENVM/VCC_ROSC voltage levels; for Fusion, monitor VCC_NVM/VCC_OSC.
- Reset signal is not properly tied off in your design. Check the Embedded Memory reset signal.
How do I recover from Embedded Flash Memory corruption?
Reprogram with original design data or 'zero-out' the pages by using the Tcl command `recover_flash_memory`.

What is a JTAG IR-Capture value?
JTAG IR-Capture value contains private and public device status values. The public status value in the value read is ISC_DONE, which indicates if the FPGA Array is programmed and enabled. The ISC_DONE signal is implemented as part of IEEE 1532 specification.

What does the ECC1/ECC2 error mean?
ECC is the Error Correction Code embedded in each Flash Memory page.
ECC1 – One bit error and correctable.
ECC2 – Two or more errors found, and not correctable.

What happens if invalid firmware is loaded into eNVM in SmartFusion2 devices?
When invalid firmware is loaded into eNVM in SmartFusion2 devices, Cortex-M3 will not be able to boot and issues reset to MSS continuously. eNVM content using View Flash Memory content will read zeroes in SmartDebug.

How can I tell if my FlashROM is programmed?
To verify that your FlashROM is programmed, read out and view the FlashROM content or perform verification with the PDB file by selecting the VERIFY or VERIFY_FROM action in FlashPro.

Can I compare serialization data?
To compare the serialization data, you can read out the FlashROM content and visually check data in the serialization region. Note that a serialization region can be an AUTO_INC or READ_FROM_FILE region. For serialization data in the AUTO_INC region, check to make sure that the data is within the specified range for that region. For READ_FROM_FILE region, you can search for a match in the source data file.

Can I tell what security options are programmed in my device?
To determine the programmed security settings, run the Device Status option from the Inspect Device dialog and examine the Security Section in the report. This section lists the security status of the FlashROM, FPGA Array and Flash Memory blocks.

Is my analog system configured?
To determine if the analog block is configured, run the Device Status option from the Inspect Device dialog and examine the Analog Block Section in the report. For example, the excerpt from the Device Status report below shows that the analog block status is operational:

```
Analog Block:
OABTR Register (HEX): 0dbe37b
3.3V (vdd33): PASS
```
1.5V (vdd15): PASS
Bandgap: PASS
-3.3V (vddn33): PASS
ADC Reference: PASS
FPGA_Good: PASS
Status: Analog Block is operational

If you read out an all zero value when examining the Analog System Configuration, it is possible that the Analog System is not configured.

You need to compare your analog system configuration with the design configuration from the Analog System Builder.

The -3.3V (vddn33) voltage is optional.

How do I interpret data in the Device Status report?

The Device Status Report generated from the FlashPro SmartDebug Feature contains the following sections:

- IDCode (see below)
- User Information
- Device State
- Analog Block (SmartFusion and Fusion only)
- Factory Data
- Security Settings

Device Status Report: IDCode

The IDCode section shows the raw IDCode read from the device. For example, in the Device Status report for an AFS600 device, you will find the following statement:

IDCode (HEX): 233261cf

The IDCode is compliant to IEEE 1149.1. The following table lists the IDCode bit assignments:

<table>
<thead>
<tr>
<th>Bit Field (little endian)</th>
<th>Example Bit Value for AFS600 (HEX)</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>Bit [31-28] (4 bits)</td>
<td>2</td>
<td>Silicon Revision</td>
</tr>
<tr>
<td>Bit [27-12] (16 bits)</td>
<td>3326</td>
<td>Device ID</td>
</tr>
<tr>
<td>Bit [11-0] (12 bits)</td>
<td>1cf</td>
<td>IEEE 1149.1 Manufacturer ID for Microsemi</td>
</tr>
</tbody>
</table>

Device Status Report: User Info

The User Information section reports the information read from the User ROW (UROW) of IGLOO, ProASIC3, SmartFusion and Fusion devices. The User Row includes user design information as well as troubleshooting information, including:

- Design name (10 characters max)
- Design check sum (16-bit CRC)
- Last programming setup used to program/erase any of the silicon features.
- FPGA Array / Fabric programming cycle count
For example:
User Information:
UROW data (HEX): 603a04e0a1c2860e59384af926fe389f
Programming Method: STAPL
Programmer: FlashPro3
Programmer Software: FlashPro vX.X
Design Name: ABCBASICDTO
Design Check Sum: 603A
Algorithm Version: 19
Array Prog. Cycle Count: 19

Table 4 · Device Status Report User Info Description

<table>
<thead>
<tr>
<th>Category</th>
<th>Field</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>User Row Data</td>
<td>(Example)</td>
<td>Raw data from User Row (UROW)</td>
</tr>
<tr>
<td></td>
<td>UROW data (HEX):</td>
<td></td>
</tr>
<tr>
<td></td>
<td>603a04e0a1c2860e59384af926fe389f</td>
<td></td>
</tr>
<tr>
<td>Programming Troubleshooting Info</td>
<td>(Example)</td>
<td>Known programming setup used. This includes: Programming method/file, programmer and software. It also includes programming Algorithm version used.</td>
</tr>
<tr>
<td></td>
<td>Programming Method: STAPL</td>
<td></td>
</tr>
<tr>
<td></td>
<td>Programmer: FlashPro3</td>
<td></td>
</tr>
<tr>
<td></td>
<td>Programmer Software: FlashPro v8.6</td>
<td></td>
</tr>
<tr>
<td></td>
<td>Algorithm Version: 19</td>
<td></td>
</tr>
<tr>
<td>Design Info</td>
<td>(Example)</td>
<td>Design name (limited to 10 characters) and check sum.</td>
</tr>
<tr>
<td></td>
<td>Design Name: ABCBASICDTO</td>
<td></td>
</tr>
<tr>
<td></td>
<td>Design Check Sum: 603A</td>
<td>Design check sum is a 16-bit CRC calculated from the fabric (FPGA Array) datastream generated for programming. If encrypted datastream is generated selected, the encrypted datastream is used for calculating the check sum.</td>
</tr>
</tbody>
</table>

Device Status Report: Device State

The device state section contains:
- IR-Capture register value, and
- The FPGA status

The IR-Capture is the value captured by the IEEE1149.1 instruction register when going through the IR-Capture state of the IEEE 1149.1 state machine. It contains information reflecting some of the states of the devices that is useful for troubleshooting.

One of the bits in the value captured is the ISC_DONE value, specified by IEEE 1532 standard. When the value is ‘1’ it means that the FPGA array/fabric is programmed and enabled. This is available for IGLOO, ProASIC3, SmartFusion and Fusion devices.

For example:
Device State:
IRCapture Register (HEX): 55
FPGA Array Status: Programmed and enabled
For a blank device:
Device State:
IRCapture Register (HEX): 51
FPGA Array Status: Not enabled

Device Status Report: Analog Block

The Analog block of the SmartFusion and Fusion devices monitors some of the key power supplies needed by the device to function. These power supply status is captured in the OABTR test register in the Analog block.

For example, if you run Device Status when the Fabric and Analog configuration is programmed and powered up successfully the report indicates:

- Analog Block:
  - OABTR Register (HEX): 0dbe3bb
  - 3.3V (vdd33): PASS
  - 1.5V (vdd15): PASS
  - Bandgap: PASS
  - -3.3V (vddn33): PASS
  - ADC Reference: PASS
  - FPGA_Good: PASS
  - Status: Analog Block is operational

Table 5 · Device Status Report - Analog Block Description

<table>
<thead>
<tr>
<th>Analog Block Status</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>OABTR Register</td>
<td>RAW data captured from the device</td>
</tr>
<tr>
<td>3.3V (vdd33)</td>
<td>Vcc33a supply status</td>
</tr>
<tr>
<td>1.5V (vdd15)</td>
<td>Vccnmv supply status</td>
</tr>
<tr>
<td>Bandgap</td>
<td>Internal bandgap supply status</td>
</tr>
<tr>
<td>ADC Reference</td>
<td>ADC reference voltage status</td>
</tr>
<tr>
<td>-3.3V (vddn33)</td>
<td>Vddn33 supply status (optional voltage)</td>
</tr>
<tr>
<td>FPGA Good</td>
<td>FPGA array or Fabric status</td>
</tr>
</tbody>
</table>

If the Fusion device is erased, the report indicates:

- Analog Block:
  - OABTR Register (HEX): 188e3ba
  - 3.3V (vdd33): PASS
  - 1.5V (vdd15): PASS
  - Bandgap: PASS
  - -3.3V (vddn33): FAIL
  - ADC Reference: FAIL
  - FPGA_Good: FAIL
  - Status: Analog Block is non-operational
  - Analog Block is not programmed
Device Status Report: Factory Data

The Factory Data section lists the Factory Serial Number (FSN).
Each of the IGLOO, ProASIC3, SmartFusion and Fusion devices has a unique 48-bit FSN.

Device Status Report: Security

The security section shows the security options for the FPGA Array, FlashROM and Flash Memory (NVM) block that you programmed into the device.

For example, using a Fusion AFS600 device:

Security:
Security Register (HEX): 000000088c01b
FlashROM
Write/Erase protection: Off
Read protection: Off
Encrypted programming: Off
FPGA Array
Write/Erase protection: Off
Verify protection: Off
Encrypted programming: Off
FlashMemory Block 0
Write protection: On
Read protection: On
Encrypted programming: Off
FlashMemory Block 1
Write protection: On
Read protection: On
Encrypted programming: Off

Table 6 · Device Status Report - Security Description

<table>
<thead>
<tr>
<th>Security Status Info</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>Security Register (HEX)</td>
<td>Raw data captured from the device's security status register</td>
</tr>
<tr>
<td>Write/Erase Protection</td>
<td>Write protection is applicable to FlashROM, FPGA Array (Fabric) and Flash Memory (NVM) blocks. When On, the Silicon feature is write/erase protected by user passkey.</td>
</tr>
<tr>
<td>Read Protection</td>
<td>Read protection is applicable to FlashROM and Flash Memory (NVM) blocks. When On, the Silicon feature is read protected by user passkey.</td>
</tr>
<tr>
<td>Verify Protection</td>
<td>Verify Protection is only applicable to FPGA Array (Fabric) only. When On, the FPGA Array require user passkey for verification.</td>
</tr>
<tr>
<td></td>
<td>Reading back from the FPGA Array (Fabric) is not supported.</td>
</tr>
<tr>
<td></td>
<td>Verification is accomplished by sending in the expected data for verification.</td>
</tr>
<tr>
<td>Encrypted Programming</td>
<td>Encrypted Programming is supported for FlashROM, FPGA Array (Fabric) and Flash Memory (NVM) blocks. When On, the silicon feature is enable for encrypted programmed. This allows field design update with encrypted datastream so the user design is protected.</td>
</tr>
</tbody>
</table>
Encrypted Programming

To allow encrypted programming of the features, the target feature cannot be Write/Erase protected by user passkey.

The security settings of each silicon feature when they are enabled for encrypted programming are listed below.

**FPGA Array (Fabric)**
- Write/Erase protection: Off
- Verify protection: Off
- Encrypted programming: On

Set automatically by Designer or FlashPro when you select to enable encrypted programming of the FPGA Array (Fabric). This setting allows the FPGA Array (Fabric) to be programmed and verified with an encrypted datastream.

**FlashROM**
- Write/Erase protection: Off
- Read protection: On
- Encrypted programming: On

Set automatically by Designer or FlashPro when you select to enable encrypted programming of the FlashROM. This setting allows the FlashROM to be programmed and verified with an encrypted datastream.

FlashROM always allows verification. If encrypted programming is set, verification has to be performed with encrypted datastream.

Designer and FlashPro automatically set the FlashROM to be read protected by user passkey when encrypted programming is enabled. This protects the content from being read out of the JTAG port after encrypted programming.

**Flash Memory (NVM) Block**
- Write/Erase protection: Off
- Read protection: On
- Encrypted programming: On

The above setting is set automatically set by Designer or FlashPro when you select to enable encrypted programming of the Flash Memory (NVM) block. This setting allows the Flash Memory (NVM) block to be programmed with an encrypted datastream.

The Flash Memory (NVM) block does not support verification with encrypted datastream.

Designer and FlashPro automatically set the Flash Memory (NVM) block to be read protected by user passkey when encrypted programming is enabled. This protects the content from being read out of the JTAG port after encrypted programming.

How do I interpret data in the Flash Memory (NVM) Status Report?

The Embedded Flash Memory (NVM) Status Report generated from the FlashPro SmartDebug feature consists of the page status of each NVM page. For example:

Flash Memory Content [ Page 34 to 34 ]
FlashMemory Page #34:
Status Register(HEX): 00090000
Status ECC2 check: Pass
Data ECC2 Check: Pass
Write Count: Pass (2304 writes)
Total number of pages with status ECC2 errors: 0
Total number of pages with data ECC2 errors: 0
Total number of pages with write count out of range: 0
FlashMemory Check PASSED for [ Page 34 to 34 ]
The 'check_flash_memory' command succeeded.
The Execute Script command succeeded.

### Table 7 · Embedded Flash Memory Status Report Description

<table>
<thead>
<tr>
<th>Flash Memory Status Info</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>Status Register (HEX)</td>
<td>Raw page status register captured from device</td>
</tr>
<tr>
<td>Status ECC2 Check</td>
<td>Check for <a href="#">ECC2 issue</a> in the page status</td>
</tr>
<tr>
<td>Data ECC2 Check</td>
<td>Check for <a href="#">ECC2 issue</a> in the page data</td>
</tr>
<tr>
<td>Write Count</td>
<td>Check if the page-write count is within the expected range.</td>
</tr>
</tbody>
</table>

The expected write count is greater than or equal to:

- 6,384 - SmartFusion devices
- 2,288 - Fusion devices

Note: Write count, if corrupted, cannot be reset to a valid value within the customer flow; invalid write count will not prevent device from being programmed with the FlashPro tool.

The write count on all good eNVM pages is set to be 2288 instead of 0 in the manufacturing flow. The starting count of the eNVM is 2288. Each time the page is programmed or erased the count increments by one. There is a Threshold that is set to 12288, which equals to 3 * 4096.

Since the threshold can only be set in multiples of 4096 ($2^{12}$), to set a 10,000 limit, the Threshold is set to 12288 and the start count is set to 2288; and thus the eNVM has a 10k write cycle limit. After the write count exceeds the threshold, the STATUS bit goes to 11 when attempting to erase/program the page.

### Encrypted Programming

To allow encrypted programming of the features, the target feature cannot be Write/Erase protected by user passkey.

The security settings of each silicon feature when they are enabled for encrypted programming are listed below.

#### FPGA Array (Fabric)

- **Write/Erase protection**: Off
- **Verify protection**: Off
- **Encrypted programming**: On

Set automatically by Designer or FlashPro when you select to enable encrypted programming of the FPGA Array (Fabric). This setting allows the FPGA Array (Fabric) to be programmed and verified with an encrypted datastream.
**FlashROM**

- Write/Erase protection: Off
- Read protection: On
- Encrypted programming: On

Set automatically by Designer or FlashPro when you select to enable encrypted programming of the FlashROM. This setting allows the FlashROM to be programmed and verified with an encrypted datastream. FlashROM always allows verification. If encrypted programming is set, verification has to be performed with encrypted datastream.

Designer and FlashPro automatically set the FlashROM to be read protected by user passkey when encrypted programming is enabled. This protects the content from being read out of the JTAG port after encrypted programming.

**Flash Memory (NVM) Block**

- Write/Erase protection: Off
- Read protection: On
- Encrypted programming: On

The above setting is set automatically set by Designer or FlashPro when you select to enable encrypted programming of the Flash Memory (NVM) block. This setting allows the Flash Memory (NVM) block to be programmed with an encrypted datastream.

The Flash Memory (NVM) block does not support verification with encrypted datastream.

Designer and FlashPro automatically set the Flash Memory (NVM) block to be read protected by user passkey when encrypted programming is enabled. This protects the content from being read out of the JTAG port after encrypted programming.
Product Support

Microsemi SoC Products Group backs its products with various support services, including Customer Service, Customer Technical Support Center, a website, electronic mail, and worldwide sales offices. This appendix contains information about contacting Microsemi SoC Products Group and using these support services.

Customer Service

Contact Customer Service for non-technical product support, such as product pricing, product upgrades, update information, order status, and authorization.

From North America, call **800.262.1060**
From the rest of the world, call **650.318.4460**
Fax, from anywhere in the world **650. 318.8044**

Customer Technical Support Center

Microsemi SoC Products Group staffs its Customer Technical Support Center with highly skilled engineers who can help answer your hardware, software, and design questions about Microsemi SoC Products. The Customer Technical Support Center spends a great deal of time creating application notes, answers to common design cycle questions, documentation of known issues and various FAQs. So, before you contact us, please visit our online resources. It is very likely we have already answered your questions.

Technical Support


Website


Contacting the Customer Technical Support Center

Highly skilled engineers staff the Technical Support Center. The Technical Support Center can be contacted by email or through the Microsemi SoC Products Group website.

Email

You can communicate your technical questions to our email address and receive answers back by email, fax, or phone. Also, if you have design problems, you can email your design files to receive assistance. We constantly monitor the email account throughout the day. When sending your request to us, please be sure to include your full name, company name, and your contact information for efficient processing of your request.

The technical support email address is soc_tech@microsemi.com.

My Cases

Microsemi SoC Products Group customers may submit and track technical cases online by going to My Cases.
Outside the U.S.
Customers needing assistance outside the US time zones can either contact technical support via email (soc_tech@microsemi.com) or contact a local sales office. Visit About Us for sales office listings and corporate contacts.

ITAR Technical Support
For technical support on RH and RT FPGAs that are regulated by International Traffic in Arms Regulations (ITAR), contact us via soc_tech@microsemi.com. Alternatively, within My Cases, select Yes in the ITAR drop-down list. For a complete list of ITAR-regulated Microsemi FPGAs, visit the ITAR web page.